

ETSI EN 301 489-1 & 17 TEST REPORT  
for  
ASUSTeK COMPUTER INC.  
Motherboard  
Model No: H170I-PLUS D3  
Brand: ASUS

Prepared for

**ASUSTeK COMPUTER INC.**  
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Prepared by

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Report Number : ACWE-RF1509005  
Date of Test : Aug.20~25, 2015  
Date of Report : Sep.15,2015

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## TEST REPORT VERIFICATION

Applicant : ASUSTeK COMPUTER INC.  
 Manufacturer#1 : MainTek Computer (Suzhou) Co., Ltd.  
 Manufacturer#2 : Danriver Technology (GZ) Inc.  
 Manufacturer#3 : Global Brands Manufacture Ltd.  
 Manufacturer#4 : First International Computer (Suzhou) Inc.  
 Manufacturer#5 : Boatek Electronic Co., Ltd.  
 Manufacturer#6 : Cal-Comp Electronics and Communications (Suzhou) Co., Ltd.  
 Manufacturer#7 : NBM Production (Dongguan) Co., Ltd.  
 Manufacturer#8 : INFO-TEK Electronics Co., Ltd.  
 Manufacturer#9 : Amtertek Computer(Shenzhen) Co., Ltd.  
 Manufacturer#10 : ONGGUAN G-PRO COMPUTER Co., Ltd.  
 EUT Description : Motherboard  
 (A) Model No. : H170I-PLUS D3  
 (B) Brand : ASUS  
 (C) Test Voltage : AC 230V, 50Hz (Via PC)

### Applicable standards:

ETSI EN301 489-1 V1.9.2: 2011-09

ETSI EN301 489-17 V2.2.1: 2012-09

(EN 55022:2010+AC:2011, EN 61000-3-2:2014 and EN 61000-3-3:2013

EN 61000-4-2:2009, EN 61000-4-3:2006+A2:2010, EN 61000-4-4:2012

EN 61000-4-5:2006, EN 61000-4-6:2014, EN 61000-4-11:2004)

The device described above is tested by Audix Technology (Wujiang) Co., Ltd. EMC Dept. to determine the maximum emission levels emanating from the device and the severity levels of the device endured and its performance Criteria. The measurement results were contained in this test report and Audix Technology (Wujiang) Co., Ltd. EMC Dept. was assumed full responsibility for the accuracy and completeness of these measurements. Also, this test report shows that the EUT is technically compliance with the ETSI EN 301-489-1 & -17 requirements.

This test report applies to above tested sample only and shall not be reproduced in part without written approval of Audix Technology (Wujiang) Co., Ltd. EMC Dept.

Date of Test: Aug.20-25, 2015

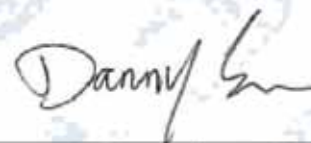
Date of Report: Sep.15,2015

Prepared by



(Emma Hu/Assistant Administrator)

Reviewer



(Danny Sun/ Section Manager)

Approved & Authorized Signer



(Ken Lu/ Assistant General Manager)

# 1 SUMMARY OF MEASUREMENTS AND RESULTS

Description of Standards and Results

The EUT have been tested according to the applicable standards as referenced below.

EMISSION					
Subclause ETSI EN 301 489-1 V1.9.2:2011-09	Description of Test Item	Standard	Limits	Results	Remark
8.2	Radiated disturbance	EN 55022:2010+AC: 2011	CLASS B	PASS	Minimum passing margin is 6.57 dB at 183.27 MHz
8.3	Conducted disturbance (DC power input/output port)	EN 55022:2010+AC: 2011	Not Applicable	Not Applicable	---
8.4	Conducted disturbance (AC mains input/output port)	EN 55022:2010+AC: 2011	CLASS B	PASS	Minimum passing margin is 6.97 dB at 0.57 MHz
8.5	Harmonic current emissions	EN 61000-3-2:2014	CLASS D	PASS	Meets the Class D requirement
8.6	Voltage fluctuations & flicker	EN 61000-3-3:2013	---	PASS	Meets the requirement
8.7	Conducted disturbance Telecommunication ports	EN 55022:2010+AC: 2011	CLASS B	PASS	Minimum passing margin is 12.97 dB at 11.96 MHz
IMMUNITY					
Subclause ETSI EN 301 489-1 V1.9.2:2011-09	Description of Test Item	Standard	Performance Criteria	Results	Observation Criteria
9.2	RF electromagnetic field (80MHz to 2700MHz)	EN 61000-4-3:2006+ A2:2010	A	PASS	A
9.3	Electrostatic discharge	EN 61000-4-2 :2009	B	PASS	A
9.4	Electrical Fast Transient/Burst	EN 61000-4-4:2012	B	PASS	A
9.5	RF common mode (0.15MHz to 80MHz)	EN 61000-4-6:2014	A	PASS	A
9.7	Voltage dips	EN	B	PASS	A
9.7	Voltage interruptions	61000-4-11:2004	C	PASS	C

9.8	Surge	EN 61000-4-5:2006	B	PASS	A
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## 2 DESCRIPTION OF PERFORMANCE CRITERION

### 2.1 Criterion (ETSI EN301 489-1/2011)

<b>Performance Criterion</b>		
1	<p>Performance Criterion for continuous phenomena applied to transmitters and receivers (CT, CR)</p>	<p>If no further details are given in the relevant part of the present document dealing with particular type of radio equipment, the following general performance Criterion for continuous phenomena shall apply.</p> <p>During and after the test, the apparatus shall continue to operate as intended. No degradation of performance or loss of function is allowed below a permissible performance level specified by the manufacturer when the apparatus is used as intended. In some cases this permissible performance level may be replaced by a permissible loss performance. During the test EUT shall not unintentionally transmit or change its actual operating state and stored data.</p> <p>If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be deduced from the product description and documentation and what the user may reasonably expect from the apparatus if used as intended.</p>
2	<p>Performance Criterion for transient phenomena applied to transmitters and receivers (TT, TR)</p>	<p>If no further details are given in the relevant part of the present document dealing with particular type of radio equipment, the following general performance Criterion for transient phenomena shall apply.</p> <p>After the test, the apparatus shall continue to operate as intended. No degradation of performance or loss of function is allowed below a permissible performance level specified by the manufacturer, when the apparatus is used as intended. In some cases this permissible performance level may be replaced by a permissible loss performance. During the EMC exposure to an electromagnetic phenomena, a degradation of performance is, however, allowed. No change of the actual mode of operation (e.g. unintended transmission) or stored data is allowed .</p> <p>If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be deduced from the product description and documentation and what the user may reasonably expect from the apparatus if used as intended.</p>
3	<p>Performance Criterion for equipment which does not provide a continuous communications link</p>	<p>For radio equipment which does not provide a continuous communication link, the performance Criterion described in the subclauses above are not appropriate, then the manufacturer shall declare, for inclusion in test report, his own specification for an acceptable level of performance or degradation of performance during and/or after the immunity tests. The performance specification shall be included in the product description and documentation. The related specifications set out in subclause 5.3 have also to be taken into account.</p> <p>The performance Criterion specified by manufacturer shall give the same degree of immunity protection as called for in the foregoing subclause.</p>
4	<p>Performance Criterion for ancillary equipment tested on a stand alone basis</p>	<p>For radio equipment which does not provide a continuous communication link, the performance Criterion described in the subclauses above are not appropriate, then the manufacturer shall declare, for inclusion in test report, his own specification for an acceptable level of performance or degradation</p> <p>The performance Criterion specified by manufacturer shall give the same degree of immunity protection as called for in the foregoing subclause.</p>

## 2.2 Performance Criterion (ETSI EN301 489-17/2012)

The performance Criteria are:

- Performance Criterion A for immunity tests with phenomena of a continuous nature (CT, CR);
- Performance Criterion B for immunity tests with phenomena of a transient nature (TT, TR);
- Performance Criterion C for immunity tests with power interruptions exceeding a certain time.

<b>Performance Criterion</b>		
<b>Criterion</b>	<b>During test</b>	<b>After test</b>
A	Shall operate as intended May show degradation of performance(note 1) Shall be no loss of function Shall be no unintentional transmissions	Shall operate as intended Shall be no degradation of performance (note 2) Shall be no loss of function Shall be no loss of stored data or user programmable functions
B	May show loss of function (one or more) May show degradation of performance(note 1) No unintentional transmissions	Functions shall be self-recoverable Shall operate as intended after recovering Shall be no degradation of performance (note 2) Shall be no loss of stored data or user programmable functions
C	May be loss of function (one or more)	Functions shall be recoverable by the operator Shall operate as intended after recovering Shall be no degradation of performance (note 2)
<p>NOTE 1: Degradation of performance during the test is understood as a degradation to a level not below a minimum performance level specified by the manufacturer for the use of the apparatus as intended. In some cases the specified minimum performance level may be replaced by a permissible degradation of performance. If the minimum performance level or the permissible performance degradation is not specified by the manufacturer then either of these may be derived from the product description and documentation (including leaflets and advertising) and what the user may reasonably expect from the apparatus if used as intended.</p> <p>NOTE 2: No degradation of performance after the test is understood as no degradation below a minimum performance level specified by the manufacturer for the use of the apparatus as intended. In some cases the specified minimum performance level may be replaced by a permissible degradation of performance. After the test no change of actual operating data or user retrievable data is allowed. If the minimum performance level or the permissible performance degradation is not specified by the manufacturer then either of these may be derived from the product description and documentation (including leaflets and advertising) and what the user may reasonably expect from the apparatus if used as intended.</p>		



### 3 GENERAL INFORMATION

3.1	Description of Device (EUT)	
	Product	: Motherboard
	Model Number	: H170I-PLUS D3
	Serial Number	: 5VP2ZM7J
	Brand	: ASUS
	Applicant	: ASUSTeK COMPUTER INC. 4F, No.150, Li-Te Rd., Peitou, Taipei 112, Taiwan
	Manufacturer # 1	: Cal-Comp Electronics and Communications (Suzhou) Co., Ltd. Wujiang Export Processing Zone, No.688, Pangjin Road, Wujiang Economic Development Zone, Jiangsu Province, China.
	Manufacturer # 2	: Danriver Technology (GZ) Inc. No.16, Baoying Dadao, Guangzhou Free Trade Zone, Guangdong, P.R.China
	Manufacturer # 3	: Boatek Electronic Co., Ltd. No.124 bubugao road, wu sha kong bavillage, chang an, dong guan, Guangdong province
	Manufacturer # 4	: Global Brands Manufacture Ltd. EMS Business unit Global Brands Manufacture Limited Yuyuan Industrial Estate, Huangjiang Town, Dongguan City, Guangdong, P.R.China
	Manufacturer # 5	: First International Computer (Suzhou) Inc. Export Processing Zone, No.200 Central Suhong Road, SuZhou Industrial Park, Jiangsu, P.R.China
	Manufacturer # 6	: MainTek Computer (Suzhou) Co., Ltd. No.233, Jinfeng Road, Suzhou City New District, Jiangsu, P.R. China
	Manufacturer # 7	: NBM Production (Dongguan) Co., Ltd. No.51 Xinju Rd., Shangjiao community, Changan Town, Dongguan City, Guangdong, P.R. China
	Manufacturer # 8	: INFO-TEK Electronics Co., Ltd. NO.183 Jinfeng Rd.,Hi-tech Development Zone Suzhou, Jiangsu, P.R. China
	Manufacturer#9	: Amtertek Computer(Shenzhen) Co., Ltd.
	Manufacturer#10	: ONGGUAN G-PRO COMPUTER Co., Ltd.
	Date of Receipt of Sample	: Aug.20, 2015
	Date of Test	: Aug.20~25, 2015

## 3.2 EUT's Specification under application

Interface Ports	:	(1) PS-2 port*1 (2) USB 3.0 port*6 (3) DP port*1 (4) HDMI port*1 (5) D-sub port*1 (6) DVI port*1 (7) RJ-45 port*1 (10M/bps, 100M/bps, 1000M/bps) (8) Audio port*3 (9) WIFI*1 (10)SPDIF*1
CPU	:	Intel 2.70GHz
Chipset	:	PCH Vendor Intel PCH Type: H170
Memory Type	:	DDR3
Memory Size	:	Min: 1024 MB; Max: 16 GB
HDMI Max. resolution	:	2560*1600@60Hz
DP Max. resolution	:	2560*1600@60Hz
DVI Max. resolution	:	2560*1600@60Hz
D-sub Max. resolution	:	1920*1200@60Hz
Highest Working Frequency ( CPU )	:	2.70GHz

## 3.3 List of all the components under test

Product	:	Brand/Model Number/Specification
CPU	:	Intel 2.70GHz
<b>Motherboard (EUT)</b>	:	<b>H170I-PLUS D3</b>
Wifi Module	:	Model: QCNFA364A LITEON/WCBN808A-AD 802.11A/B/G/N/AC WLAN+BT4.1
HDD	:	Seagate,ST3750528AS, 750GB
RAM	:	Crucial, CT102464BA160B.16FED
Switching Power Supply	:	Brand: FSP GROUP INC. Model No.: FSP400-60EPN Input: AC 100-240V, 6-3A, 50-60Hz Output:DC(+3.3V/24.0A; +5V/15.0A; +12V1/17.0A; +12V2/17.0A; +5Vsb/2.5A -12V/0.3A;) 400W (+3.3V&+5V=120W Max) (+12V1&+12V2=336W Max); DC Power cord: Unshielded, Undetachable, 0.4m

## 3.4 Operating Condition of EUT

EUT Exercise Program and Condition	
Operating System	Windows 7
Test Program	“BurnIn Test V 6.0”
Graphic Controller	Display scrolling “H” pattern (Font: Arial, Size: 11) with respective resolution.
Audio Controller	Run the program “Windows Media Player” and play 1kHz audio signal.
LAN Controller (10M/bps)	Data transfer to host PC (pin test)
LAN Controller (100M/bps & 1G/bps)	Data transfer to host PC (tfgn.exe.)
One USB Port	Write operation to USB peripherals (WINTHRAX.exe.)
Other USB Ports	Read operation to USB peripherals (WINTHRAX.exe.)
PS-2 Port	Write operation to PS-2 peripherals.
USB port	Connect to Printer

## 3.5 Tested Supporting System Details

## 3.5.1 USB Mouse

Manufacturer : HP  
 Model Number : UAE86  
 Serial Number : N/A  
 BSMI ID : R41108  
 Data Cable : Shielded, Undetachable, 1.8m

## 3.5.2 PS-2 Keyboard

Manufacturer : HP  
 Model Number : KB-0316  
 Serial Number : **537745-AA1**  
 BSMI ID : R33001  
 Data Cable : Shielded, Undetachable, 1.8m

## 3.5.3 LCD Monitor #1

Manufacturer : DELL  
 Model Number : 3008WFPt  
 Serial Number : CN-ORW915-71618-84T-102L  
 Display Cable : Shielded, Detachable, 1.8m  
 AC Power Cord : Unshielded, Detachable, 1.8m

## 3.5.4 LCD Monitor #2

Manufacturer : DELL  
 Model Number : U3011t  
 Serial Number : CN-0PH5NY-74445-17F-060L  
 HDMI Cable : Shielded, Detachable, 1.8m  
 AC Power Cord : Unshielded, Detachable, 1.8m

## 3.5.5 LCD Monitor #3

Manufacturer : DELL  
 Model Number : U3014t  
 Serial Number : CN-0P1V6N-74445-34J-110L  
 D-sub Cable : Shielded, Detachable, 1.8m. 2core  
 DVI Cable : Shielded, Detachable, 1.8m. 2core  
 AC Power Cord : Unshielded, Detachable, 1.8m

## 3.5.6 Walkman

Manufacturer : WINGO  
 Model Number : SP-2311

Serial Number	:	o143360731
Audio Cable	:	Shielded, Detachable, 1.8m
3.5.7 Speaker		
Manufacturer	:	Plank
Model Number	:	CAT-522
Serial Number	:	204896
BSMI ID	:	R41307
Audio Cable	:	Shielded, Detachable, 1.8m
SPDIF Cable	:	Shielded, Detachable, 1.8m
3.5.8 Printer		
Manufacturer	:	HP
Model Number	:	DESKJET3918
Serial Number	:	CN64S1N0T6
USB Cable	:	Shielded, Detachable, 2.0m
AC Adapter	:	HP/090-4397 I/P: AC100-240V, 50-60Hz, 500mA, O/P: DC +32Vdc, 500mA max; +15Vdc, 530mA max AC Cord: Unshielded, Detachable, 1.8m DC Cord: Unshielded, Undetachable, 1.8m, 1 ferrite core
3.5.9 Earphone #1		
Manufacturer	:	SALAR
Model Number	:	V81
Audio Cable	:	Unshielded, Undetachable, 2.2m
3.5.10 USB HDD # 1		
Manufacturer	:	BUFFALO
Model Number	:	HD-HX1.OTU3-AP
Serial Number	:	45564800402028
Data Cable	:	Shielded, Detachable, 1.0m
3.5.11 USB HDD # 2		
Manufacturer	:	BUFFALO
Model Number	:	HD-HX1.OTU3-AP
Serial Number	:	45564800402035
Data Cable	:	Shielded, Detachable, 1.0m
3.5.12 USB HDD # 3		
Manufacturer	:	BUFFALO
Model Number	:	HD-HX1.OTU3-AP

Serial Number : 45564800402202  
Data Cable : Shielded, Detachable, 1.0m

3.5.13 USB HDD # 4

Manufacturer : BUFFALO  
Model Number : HD-HX1.OTU3-AP  
Serial Number : 45564800401977  
Data Cable : Shielded, Detachable, 1.0m

3.5.14 AC Power Cord: Unshielded, Detachable, 1.8m, 3C (Connecting to PC)

For Conducted Disturbance Measurement:

3.5.15 RJ-45 Cable \*1: Unshielded, Detachable, 9m (Connecting between AE and ISN)

3.5.16 RJ-45 Cable \*1: Shielded, Detachable, 9m (Connecting between AE and ISN)

3.5.17 RJ-45 Cable \*1: Unshielded, Detachable, 1.0m (Connecting between EUT and ISN)

3.5.18 RJ-45 Cable \*1: Shielded, Detachable, 1.0m (Connecting between EUT and ISN)

For Radiated Disturbance Measurement (10m Chamber):

3.5.19 RJ-45 Cable \*1: Unshielded, Detachable, 25m (Connecting between EUT and PC)

- 3.6 Description of Test Facility
- Name of Firm : **Audix Technology (Wujiang) Co., Ltd. EMC Dept.**
- Site Location : No. 1289 Jiangxing East Road, the Eastern Part of Wujiang Economic Development Zone  
Jiangsu China 215200
- Test Facilities : **No.1 10m semi-anechoic chamber**  
**No. 1 conducted shielding enclosure**  
**The Complex Immunity Test Room**  
**RS&CS Test Room**
- NVLAP Lab Code : 200786-0  
Valid until on Sep. 30, 2016  
(NVLAP is a signatory member of ILAC MRA)  
Remark: This report shall not be imply endorsement, certification or approval by NVLAP, NIST, or any agency of the U.S. Federal Government.

## 3.7 Measurement Uncertainty

Test Item	Range Frequency	Uncertainty
No.1 Conducted Shielding Enclosure		
Conducted Disturbance Measurement at mains port	0.15MHz ~ 30MHz	± 3.30dB
Conducted Disturbance Measurement at telecommunication port	0.15MHz ~ 30MHz	± 3.80dB
At 10m Semi-Anechoic Chamber		
Radiated Disturbance Measurement (Distance 10m)	30MHz ~ 1000MHz	± 3.96dB (Horizontal)
		± 4.17dB (Vertical)
Radiated Disturbance Measurement (Distance 3m)	1000MHz ~ 6000MHz	± 5.13dB

Remark : Uncertainty =  $ku_c(y)$

## 4 CONDUCTED DISTURBANCE AT MAINS TERMINALS TEST

### 4.1 Test Equipment

The following test equipment are used during the power-line conducted test in a shielded room:

#### 4.1.1 For AC Mains Port

Item	Type	Manufacturer	Model No.	Serial No.	Last Cal.	Next Cal.
1.	Test Receiver	R & S	ESCI	100839	2015-01-05	2016-01-04
2.	A.M.N.	R&S	ESH2-Z5	100153	2015-05-15	2016-05-14
3.	L.I.S.N	Kyoritsu	KNW-407	8-1793-4	2015-07-03	2016-07-03
4.	Pulse Limiter	R&S	ESH3-Z2	100605	2015-07-03	2016-07-03
5.	RF Cable	Harbour Industries	RG400	001	2015-01-05	2016-01-04
6.	Software	Audix/e3(6.7.0313)				

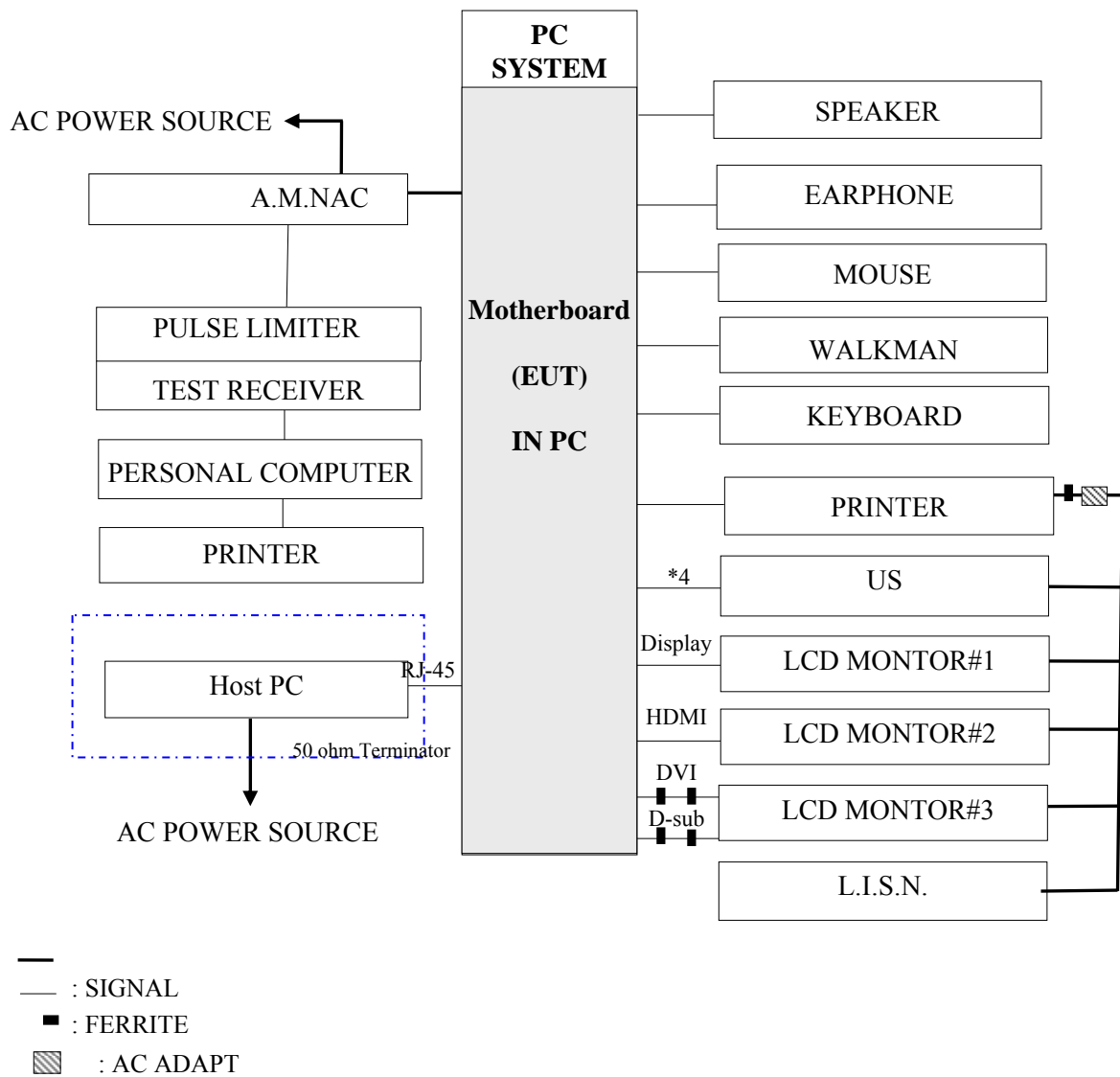
#### 4.1.2 For Telecommunication Port

Item	Type	Manufacturer	Model No.	Serial No.	Last Cal.	Next Cal.
1.	Test Receiver	R & S	ESCI	100839	2015-01-05	2016-01-04
2.	A.M.N.	R&S	ESH2-Z5	100153	2015-05-15	2016-05-14
3.	L.I.S.N	Kyoritsu	KNW-407	8-1793-4	2015-07-03	2016-07-03
4.	I.S.N.	TESEQ	T800	30804	2015-07-03	2016-07-03
5.	C.D.N	TESEQ	CDN ST08A	36281	2014-12-09	2015-12-08
6.	Pulse Limiter	R&S	ESH3-Z2	100605	2015-07-03	2016-07-03
7.	RF Cable	Harbour Industries	RG400	001	2015-01-05	2016-01-04
8.	Software	Audix/e3(6.7.0313)				

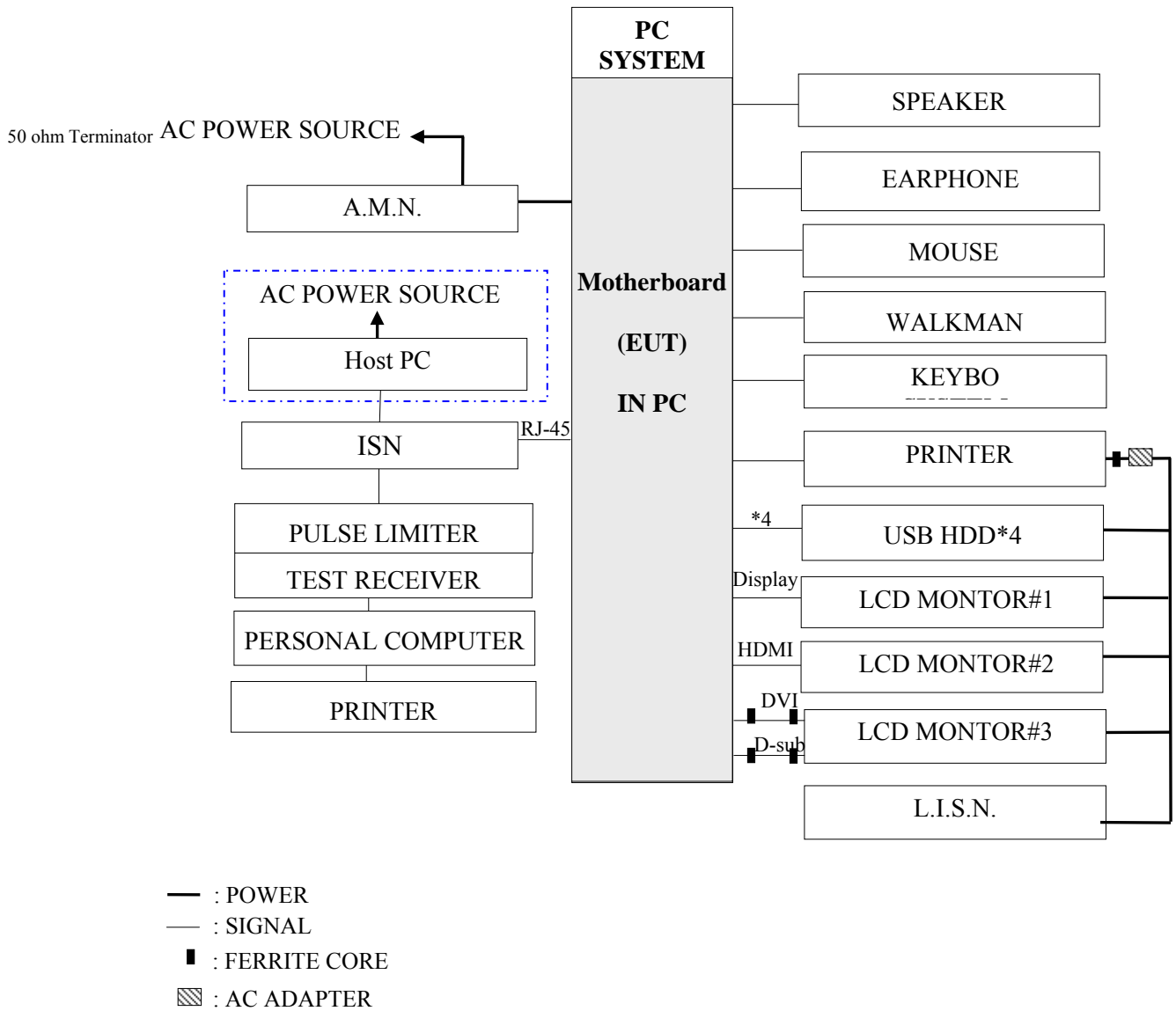


4.2 Block Diagram of Test Setup

4.2.1 for AC Mains Port



4.2.2 for Telecommunication Port



#### 4.3 Limits for Conducted Emissions from AC Mains Port (ETSI EN 301 489-1 V1.9.2:2011-09 Subclause 8.4 (EN55022,Class B))

Frequency range	Limit (quasi-peak)	Limit (average)
150kHz ~ 500kHz	66 dB $\mu$ V ~ 56 dB $\mu$ V	56 dB $\mu$ V ~ 46 dB $\mu$ V
500kHz ~ 5MHz	56 dB $\mu$ V	46 dB $\mu$ V
5MHz ~ 30MHz	60 dB $\mu$ V	50 dB $\mu$ V

Remark 1. The limit decreases linearly with the logarithm of the frequency in the range 0.15MHz to 0.5MHz.

2. If the average limit is met when using a Quasi-Peak detector, the EUT shall be deemed to meet both limits and measurement with the average detector is unnecessary.
3. The lower limit applies at the band edges.

#### 4.4 Limits for Conducted Emissions from the telecommunication ports ETSI EN 301 489-1 V1.9.2:2011-09 Sub clause 8.7 (EN55022,Class B)

Frequency	Voltage Limits(dB $\mu$ V)		Current Limits(dB $\mu$ A)	
	Quasi-Peak	Average	Quasi-Peak	Average
0.15MHz ~ 0.5MHz	84 ~ 74	74 ~ 64	40 ~ 30	30 ~ 20
0.5MHz ~ 30MHz	74	64	30	20

Remark 1. The limit decreases linearly with the logarithm of the frequency in the range 0.15MHz to 0.5MHz.

#### 4.5 Test Procedure

The measuring process is according to the standard of EN 55022, The standard of EN 55022 and laboratory internal procedure TKC-301-004.

##### 4.5.1 For AC Main Port

In the conducted emission measurement, the EUT and all peripheral devices were set up on a non-metallic table which was 0.8 meter height above the ground plane, and 0.4 meter far away from the vertical plane. The mains cable of the EUT connected to one Artificial Main Network(AMN). All other unit of the EUT and AE connected to a second Line Impedance Stabilization Network(L.I.S.N.). The telecommunication cable connected to the AE through a Impedance Stabilization Network(ISN) which terminated a 50 $\Omega$  resistor. For the measurement, the A.M.N measuring port was terminated by a 50 $\Omega$  measuring equipment and the second L.I.S.N measuring port was terminated by a 50 $\Omega$  terminator. All measurements were done between the phase lead and the reference ground, and between the neutral lead and the reference ground. All cables or wires placement were verified to find out the maximum emission.

##### 4.5.2 For Telecommunication Port

The setup is the same as conduction besides this, connecting between AE and telecommunication port through ISN. Each phase of telecommunication wire is measured to evaluate the maximum conducted emission in accordance with clause 9 of EN 55022.

The bandwidth of measuring receiver was set at 9 kHz.

The required frequency band (0.15 MHz ~ 30 MHz) was pre-scanned with peak detector, the final measurement was measured with quasi-peak detector and average detector. (If the average limit is met when using a quasi-peak detector, the average detector is unnecessary).

The emission level is calculated automatically by the test system which uses the following equation:

Emission level (dB $\mu$ V) = Reading (dB $\mu$ V) + A.M.N / I.S.N. factor (dB) + Cable loss (dB). (Cable loss includes pulse limiter loss)

## 4.6 Measurement Results

## 4.6.1 AC main port Measurement Results

**PASSED**

EUT with the following configuration is performed during this section testing and all the test results are listed in next pages.

Test Date: Aug.22,2015

Temperature: 21.4

Humidity: 59%

Item	Test Mode	Reference Test Data No.	
		Neutral	Line
<b>1</b>	<b>WLAN+BT Operating</b>	<b># 29</b>	<b># 30</b>

NOTE 1- ' ' means the worst test mode.

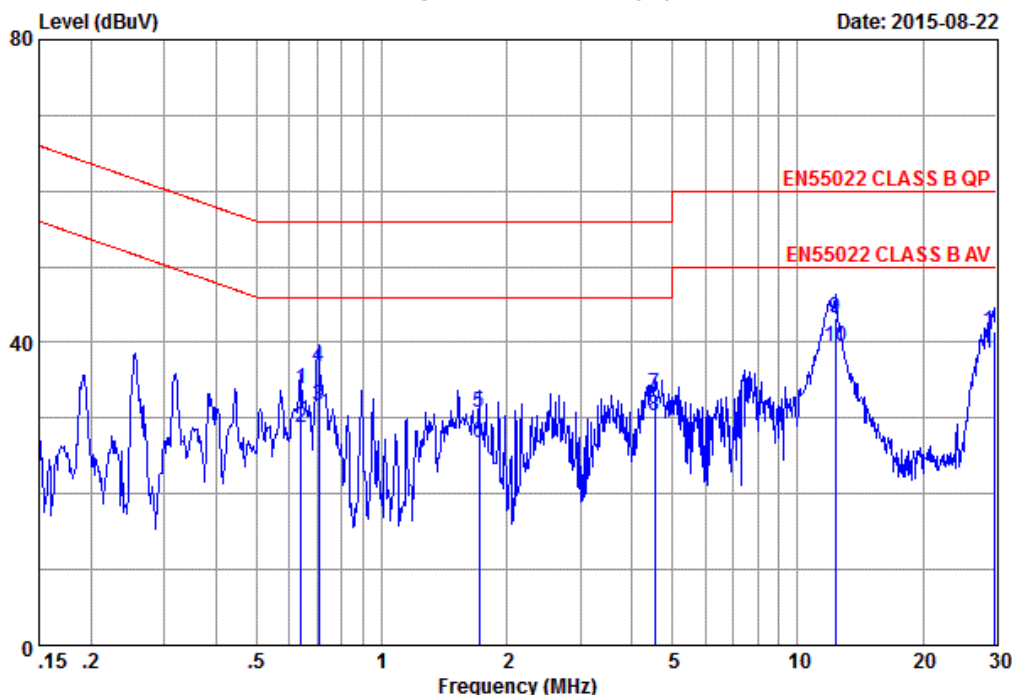
NOTE 2- The worst emission is detected at 0.57 MHz with emission level of 39.03 dB ( $\mu$ V) and with AV detector (limit is 46.00 dB ( $\mu$ V)), when the Line of the EUT is connected to A.M.N.

EUT with the following configuration is performed during this section testing and all the test results are listed in next pages.



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Data: 29 File: F:\2015Test Data\Report\8\G1508022.EM6 (48)



Site no. : No.1 Conducted shielding Enclosure Data no. : 29  
 AMN/LISN : ESH2-Z5-1505 Phase : NEUTRAL  
 Limit : EN55022 CLASS B QP  
 Env. / Ins. : 21.4C&59%/ESCI Engineer : Miller  
 EUT : Motherboard  
 M/N : H170I-PLUS D3  
 Power Rating : 230Vac/50Hz  
 Test mode : WLAN+BT Operating  
 Memo : Intel(R) Core(TM) i5-6400 CPU@2.70GHz  
 : BIOS:0302

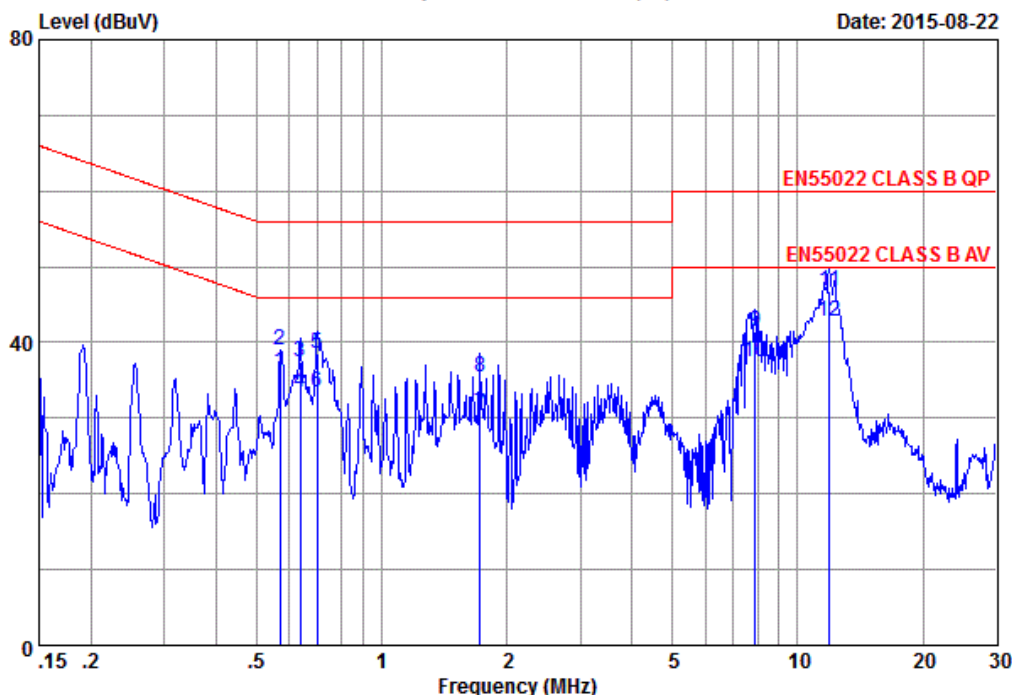
Freq. (MHz)	AMN Factor (dB)	Cable Loss (dB)	Reading (dBuV)	Emission Level (dBuV)	Limits (dBuV)	Margin (dB)	Remark
1	0.64	0.17	9.89	23.76	56.00	22.18	QP
2	0.64	0.17	9.89	18.76	46.00	17.18	Average
3	0.70	0.17	9.89	21.66	46.00	14.28	Average
4	0.70	0.17	9.89	26.66	56.00	19.28	QP
5	1.72	0.20	9.92	20.61	56.00	25.27	QP
6	1.72	0.20	9.92	16.61	46.00	19.27	Average
7	4.53	0.29	9.96	23.04	56.00	22.71	QP
8	4.53	0.29	9.96	20.04	46.00	15.71	Average
9	12.32	0.49	10.05	32.79	60.00	16.67	QP
10	12.32	0.49	10.05	28.79	50.00	10.67	Average
11	29.68	0.76	10.22	30.52	60.00	18.50	QP
12	29.68	0.76	10.22	27.52	50.00	11.50	Average

Remarks:  
 1. Emission Level= AMN factor + Cable loss + Reading .



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Data: 30 File: F:\2015Test Data\Report\8\G1508022.EM6 (48)



Site no. : No.1 Conducted shielding Enclosure Data no. : 30  
 AMN/LISN : ESH2-Z5-1505 Phase : LINE  
 Limit : EN55022 CLASS B QP  
 Env. / Ins. : 21.4C&59%/ESCI Engineer : Miller  
 EUT : Motherboard  
 M/N : H170I-PLUS D3  
 Power Rating : 230Vac/50Hz  
 Test mode : WLAN+BT Operating  
 Memo : Intel(R) Core(TM) i5-6400 CPU@2.70GHz  
 : BIOS:0302

	Freq. (MHz)	AMN Factor (dB)	Cable Loss (dB)	Reading (dBuV)	Emission Level (dBuV)	Limits (dBuV)	Margin (dB)	Remark
1	0.57	0.17	9.88	25.97	36.02	56.00	19.98	QP
2	0.57	0.17	9.88	28.98	39.03	46.00	6.97	Average
3	0.64	0.18	9.89	27.40	37.47	56.00	18.53	QP
4	0.64	0.18	9.89	23.40	33.47	46.00	12.53	Average
5	0.70	0.18	9.89	28.46	38.53	56.00	17.47	QP
6	0.70	0.18	9.89	23.46	33.53	46.00	12.47	Average
7	1.73	0.20	9.92	20.42	30.54	46.00	15.46	Average
8	1.73	0.20	9.92	25.42	35.54	56.00	20.46	QP
9	7.89	0.31	10.00	31.14	41.45	60.00	18.55	QP
10	7.89	0.31	10.00	27.14	37.45	50.00	12.55	Average
11	11.93	0.38	10.04	36.34	46.76	60.00	13.24	QP
12	11.93	0.38	10.04	32.34	42.76	50.00	7.24	Average

Remarks:  
 1. Emission Level= AMN factor + Cable loss + Reading .

## 4.6.2 Telecommunication Port Measurement Results

EUT with the following worst test modes were performed during this section testing and all the test results are listed in next pages.

Test Date: Aug.22,2015      Temperature: 21.4      Humidity: 59%

Item	Test Condition	Reference Test Data No.
No shielding		
<b>1</b>	<b>RJ-45 10Mbps</b>	<b># 34</b>
2	RJ-45 100Mbps	# 35
3	RJ-45 1000Mbps	# 36
Shielding		
4	RJ-45 10Mbps	#46
5	RJ-45 100Mbps	#47
6	RJ-45 1000Mbps	#48

NOTE 1 - ' ' means the worst test mode.

NOTE 2 - The worst emission is detected at 11.96 MHz with emission level of 51.03 dB ( $\mu$ V) and with AV detector (limit is 64.00 dB ( $\mu$ V)), when the RJ-45 port (under 10M/bps) of the EUT is connected to I.S.N.

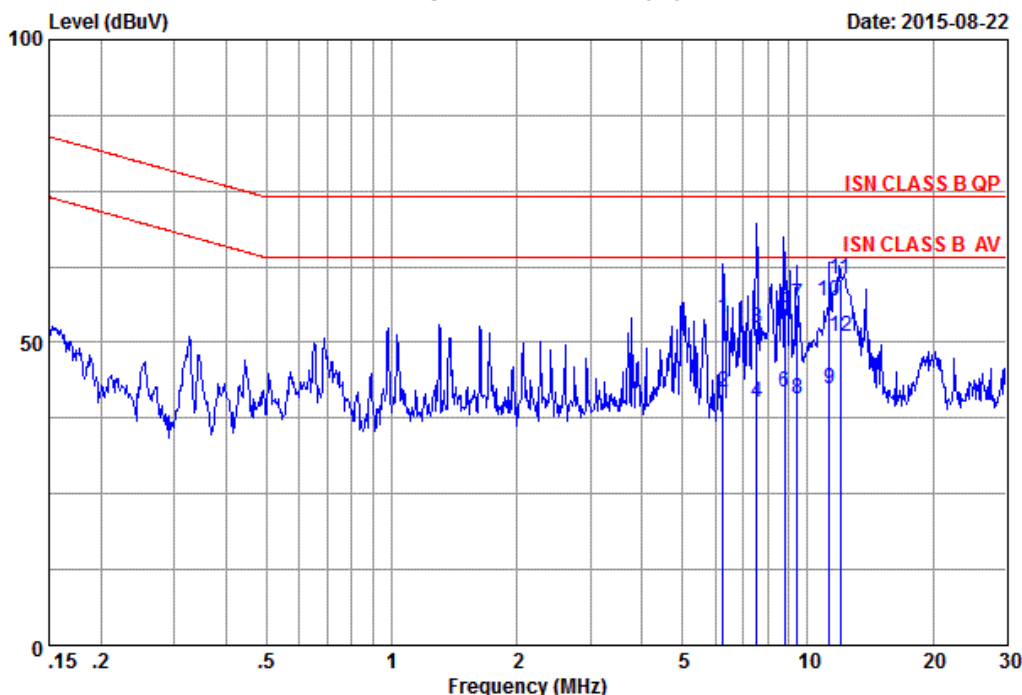


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Data: 34

File: F:\2015Test Data\Report\8\G1508022.EM6 (48)

Date: 2015-08-22



Site no. : No.1 Conducted shielding Enclosure Data no. : 34  
 AMN/LISN : T800-CAT.5-1507 Phase :  
 Limit : ISN CLASS B QP  
 Env. / Ins. : 21.4C&59%/ESCI Engineer : Miller  
 EUT : Motherboard  
 M/N : H170I-PLUS D3  
 Power Rating : 230Vac/50Hz  
 Test mode : RJ45 10Mbps  
 Memo : Intel(R) Core(TM) i5-6400 CPU@2.70GHz  
 : BIOS:0302  
 : noshiedling

	Freq. (MHz)	ISN Factor (dB)	Cable Loss (dB)	Reading (dBuV)	Emission Level (dBuV)	Limits (dBuV)	Margin (dB)	Remark
1	6.25	9.57	9.98	34.60	54.15	74.00	19.85	QP
2	6.25	9.57	9.98	22.10	41.65	64.00	22.35	Average
3	7.55	9.56	10.00	32.80	52.36	74.00	21.64	QP
4	7.55	9.56	10.00	20.50	40.06	64.00	23.94	Average
5	8.80	9.56	10.01	36.10	55.67	74.00	18.33	QP
6	8.80	9.56	10.01	22.10	41.67	64.00	22.33	Average
7	9.45	9.56	10.02	36.80	56.38	74.00	17.62	QP
8	9.45	9.56	10.02	21.10	40.68	64.00	23.32	Average
9	11.25	9.58	10.03	22.80	42.41	64.00	21.59	Average
10	11.25	9.58	10.03	37.10	56.71	74.00	17.29	QP
11	11.96	9.58	10.04	40.81	60.43	74.00	13.57	QP
12	11.96	9.58	10.04	31.41	51.03	64.00	12.97	Average

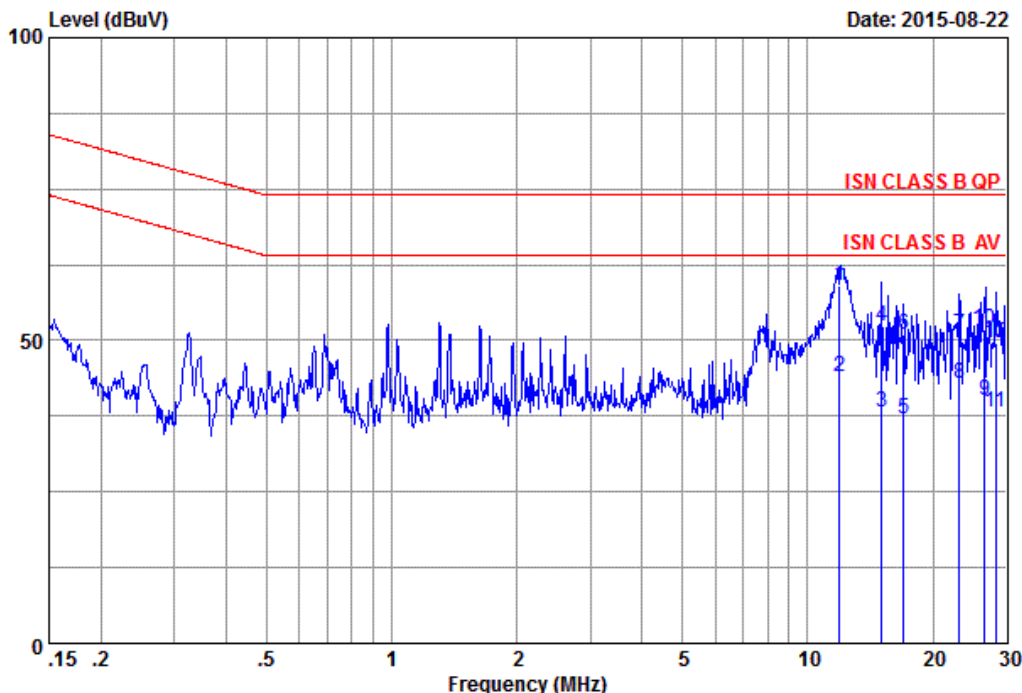
Remarks:  
 1. Emission Level= ISN factor + Cable loss + Reading .





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Data: 35 File: F:\2015Test Data\Report\8\G1508022.EM6 (48) Date: 2015-08-22



Site no. : No.1 Conducted shielding Enclosure Data no. : 35  
 AMN/LISN : T800-CAT.5-1507 Phase :  
 Limit : ISN CLASS B QP  
 Env. / Ins. : 21.4C&59%/ESCI Engineer : Miller  
 EUT : Motherboard  
 M/N : H170I-PLUS D3  
 Power Rating : 230Vac/50Hz  
 Test mode : RJ45 100Mbps  
 Memo : Intel(R) Core(TM) i5-6400 CPU@2.70GHz  
 : BIOS:0302  
 : noshiedling

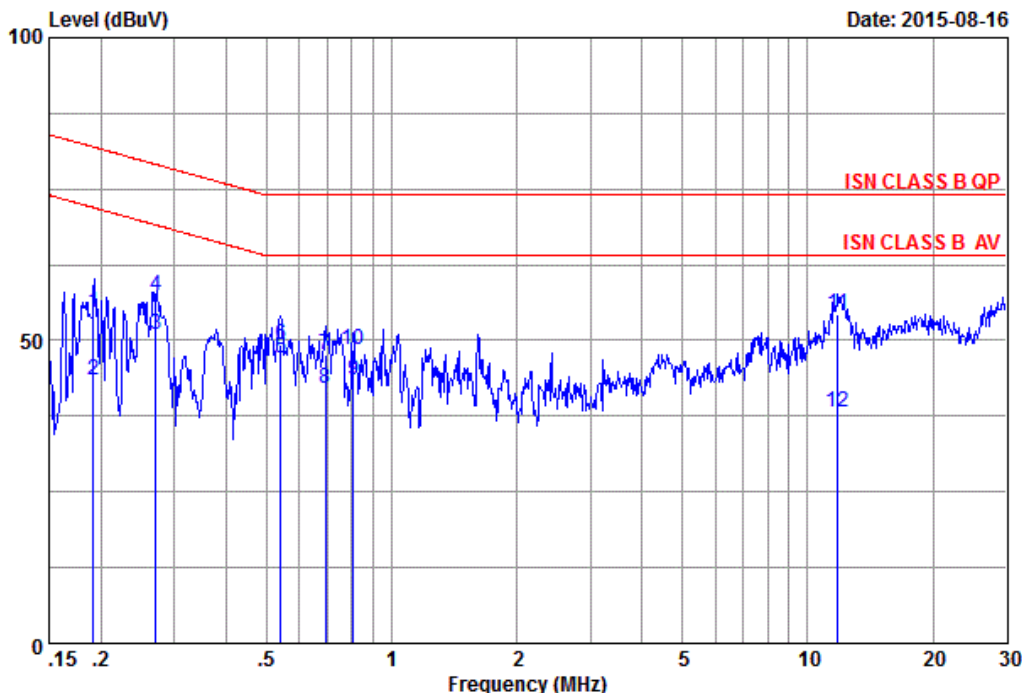
Freq. (MHz)	ISN Factor (dB)	Cable Loss (dB)	Reading (dBuV)	Emission Level (dBuV)	Limits (dBuV)	Margin (dB)	Remark
1	11.93	9.58	10.04	39.40	59.02	74.00	14.98 QP
2	11.93	9.58	10.04	24.50	44.12	64.00	19.88 Average
3	15.08	9.62	10.07	18.50	38.19	64.00	25.81 Average
4	15.08	9.62	10.07	32.80	52.49	74.00	21.51 QP
5	17.03	9.64	10.09	17.20	36.93	64.00	27.07 Average
6	17.03	9.64	10.09	31.20	50.93	74.00	23.07 QP
7	23.19	9.75	10.14	31.11	51.00	74.00	23.00 QP
8	23.19	9.75	10.14	23.11	43.00	64.00	21.00 Average
9	26.69	9.83	10.18	20.10	40.11	64.00	23.89 Average
10	26.69	9.83	10.18	31.90	51.91	74.00	22.09 QP
11	28.31	9.86	10.20	18.20	38.26	64.00	25.74 Average
12	28.31	9.86	10.20	29.60	49.66	74.00	24.34 QP

Remarks:  
 1. Emission Level= ISN factor + Cable loss + Reading .



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Data: 36 File: F:\2015Test Data\Report\8\G1508022.EM6 (48)



Site no. : No.1 Conducted shielding Enclosure Data no. : 36  
 AMN/LISN : T800-CAT.5-1507 Phase :  
 Limit : ISN CLASS B QP  
 Env. / Ins. : 21.5C&58%/ESCI Engineer : Miller  
 EUT : Motherboard  
 M/N : H170I-PLUS D3  
 Power Rating : 230Vac/50Hz  
 Test mode : RJ45 1000Mbps  
 Memo : Intel(R) Core(TM) i5-6400 CPU@2.70GHz  
 : BIOS:0302  
 : noshiedling

Freq. (MHz)	ISN Factor (dB)	Cable Loss (dB)	Reading (dBuV)	Emission Level (dBuV)	Limits (dBuV)	Margin (dB)	Remark
1	0.19	10.18	9.87	34.51	54.56	81.95	27.39 QP
2	0.19	10.18	9.87	23.51	43.56	71.95	28.39 Average
3	0.27	10.08	9.88	30.89	50.85	69.09	18.24 Average
4	0.27	10.08	9.88	37.29	57.25	79.09	21.84 QP
5	0.54	9.78	9.88	27.30	46.96	64.00	17.04 Average
6	0.54	9.78	9.88	29.70	49.36	74.00	24.64 QP
7	0.69	9.74	9.89	28.00	47.63	74.00	26.37 QP
8	0.69	9.74	9.89	22.30	41.93	64.00	22.07 Average
9	0.81	9.71	9.89	23.80	43.40	64.00	20.60 Average
10	0.81	9.71	9.89	28.90	48.50	74.00	25.50 QP
11	11.80	9.58	10.04	34.70	54.32	74.00	19.68 QP
12	11.80	9.58	10.04	18.50	38.12	64.00	25.88 Average

Remarks:  
 1. Emission Level= ISN factor + Cable loss + Reading .

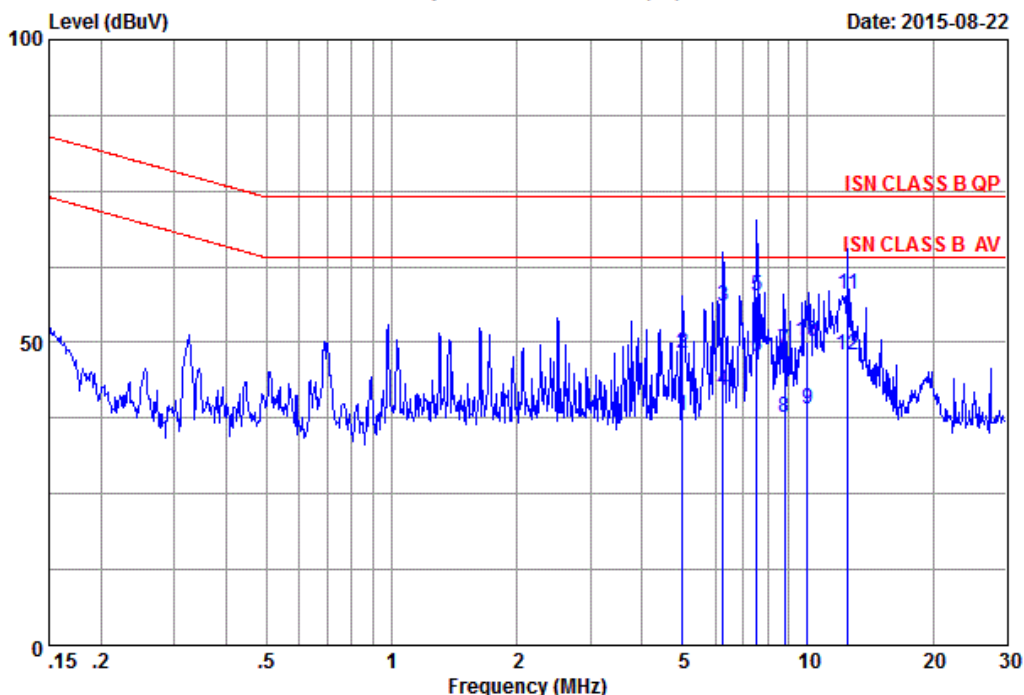


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Data: 46

File: F:\2015Test Data\Report\8\G1508022.EM6 (48)

Date: 2015-08-22



Site no. : No.1 Conducted shielding Enclosure Data no. : 46  
 AMN/LISN : ST08A 141209 Phase :  
 Limit : ISN CLASS B QP  
 Env. / Ins. : 21.4C&59%/ESCI Engineer : Miller  
 EUT : Motherboard  
 M/N : H170I-PLUS D3  
 Power Rating : 230Vac/50Hz  
 Test mode : RJ45 10Mbps  
 Memo : Intel(R) Core(TM) i5-6400 CPU@2.70GHz  
 : BIOS:0302  
 : shiedling

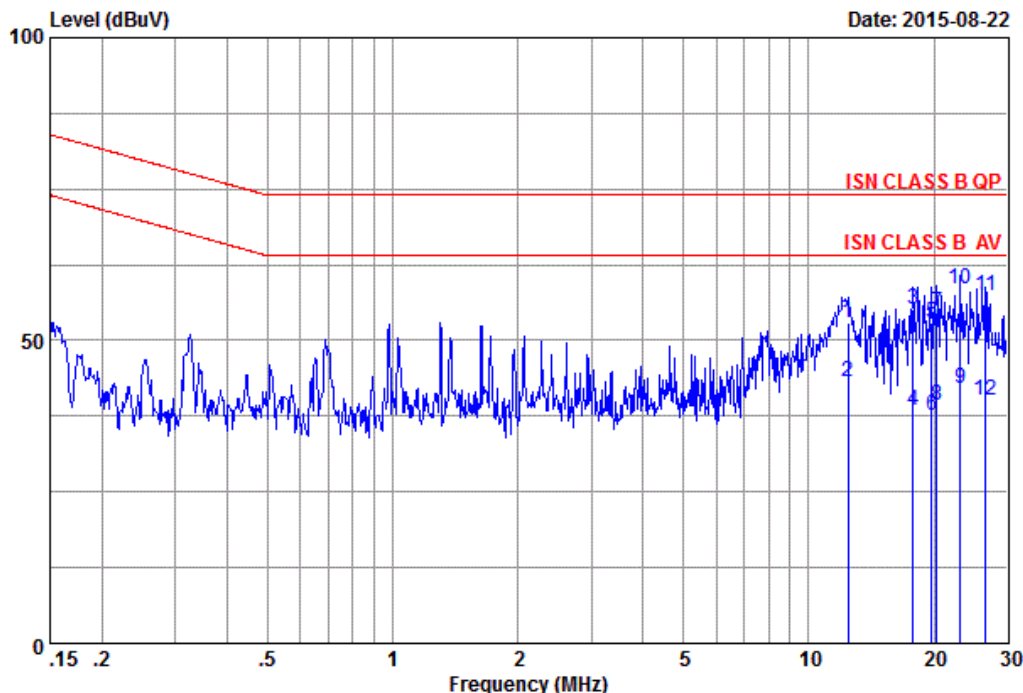
Freq. (MHz)	ISN Factor (dB)	Cable Loss (dB)	Reading (dBuV)	Emission Level (dBuV)	Limits (dBuV)	Margin (dB)	Remark	
1	5.00	9.76	9.96	18.10	37.82	64.00	26.18	Average
2	5.00	9.76	9.96	28.60	48.32	74.00	25.68	QP
3	6.25	9.82	9.98	36.10	55.90	74.00	18.10	QP
4	6.25	9.82	9.98	22.30	42.10	64.00	21.90	Average
5	7.55	9.87	10.00	37.90	57.77	74.00	16.23	QP
6	7.55	9.87	10.00	27.70	47.57	64.00	16.43	Average
7	8.80	9.94	10.01	28.79	48.74	74.00	25.26	QP
8	8.80	9.94	10.01	17.59	37.54	64.00	26.46	Average
9	10.00	10.00	10.02	18.90	38.92	64.00	25.08	Average
10	10.00	10.00	10.02	30.20	50.22	74.00	23.78	QP
11	12.50	10.09	10.05	37.89	58.03	74.00	15.97	QP
12	12.50	10.09	10.05	27.69	47.83	64.00	16.17	Average

Remarks:  
 1. Emission Level= ISN factor + Cable loss + Reading .



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Data: 47 File: F:\2015Test Data\Report\8\G1508022.EM6 (48)



Site no. : No.1 Conducted shielding Enclosure Data no. : 47  
 AMN/LISN : ST08A 141209 Phase :  
 Limit : ISN CLASS B QP  
 Env. / Ins. : 21.4C&59%/ESCI Engineer : Miller  
 EUT : Motherboard  
 M/N : H170I-PLUS D3  
 Power Rating : 230Vac/50Hz  
 Test mode : RJ45 100Mbps  
 Memo : Intel(R) Core(TM) i5-6400 CPU@2.70GHz  
 : BIOS:0302  
 : shiedling

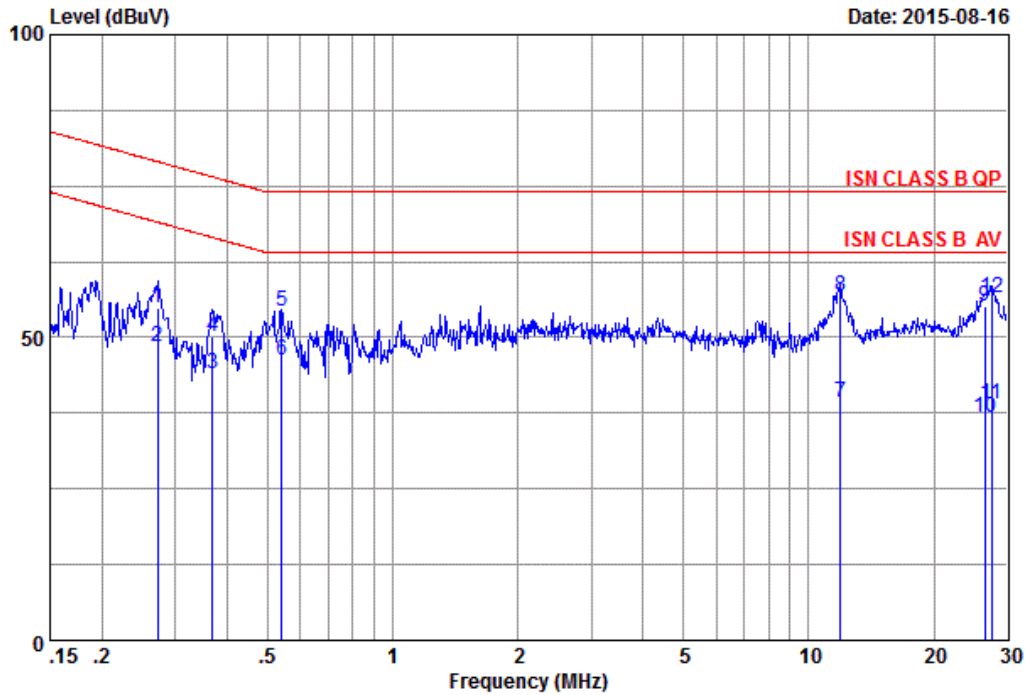
	Freq. (MHz)	ISN Factor (dB)	Cable Loss (dB)	Reading (dBuV)	Emission Level (dBuV)	Limits (dBuV)	Margin (dB)	Remark
1	12.44	10.08	10.05	32.70	52.83	74.00	21.17	QP
2	12.44	10.08	10.05	23.00	43.13	64.00	20.87	Average
3	17.83	10.22	10.09	34.91	55.22	74.00	18.78	QP
4	17.83	10.22	10.09	18.11	38.42	64.00	25.58	Average
5	19.77	10.26	10.11	32.60	52.97	74.00	21.03	QP
6	19.77	10.26	10.11	17.20	37.57	64.00	26.43	Average
7	20.32	10.29	10.11	34.30	54.70	74.00	19.30	QP
8	20.32	10.29	10.11	18.90	39.30	64.00	24.70	Average
9	23.13	10.43	10.14	21.60	42.17	64.00	21.83	Average
10	23.13	10.43	10.14	38.00	58.57	74.00	15.43	QP
11	26.60	10.58	10.18	36.60	57.36	74.00	16.64	QP
12	26.60	10.58	10.18	19.30	40.06	64.00	23.94	Average

Remarks:  
 1. Emission Level= ISN factor + Cable loss + Reading .



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Data: 48 File: F:\2015Test Data\Report\8\G1508022.EM6 (48) Date: 2015-08-16



Site no. : No.1 Conducted shielding Enclosure Data no. : 48  
 AMN/LISN : ST08A 141209 Phase :  
 Limit : ISN CLASS B QP  
 Env. / Ins. : 21.5C&58%/ESCI Engineer : Miller  
 EUT : Motherboard  
 M/N : H170I-PLUS D3  
 Power Rating : 230Vac/50Hz  
 Test mode : RJ45 1000Mbps  
 Memo : Intel(R) Core(TM) i5-6400 CPU@2.70GHz  
 : BIOS:0302  
 : shiedling

Freq. (MHz)	ISN Factor (dB)	Cable Loss (dB)	Reading (dBuV)	Emission Level (dBuV)	Limits (dBuV)	Margin (dB)	Remark	
1	0.27	9.77	9.88	35.09	54.74	79.06	24.32	QP
2	0.27	9.77	9.88	28.79	48.44	69.06	20.62	Average
3	0.37	9.75	9.88	24.30	43.93	66.52	22.59	Average
4	0.37	9.75	9.88	30.60	50.23	76.52	26.29	QP
5	0.54	9.74	9.88	34.70	54.32	74.00	19.68	QP
6	0.54	9.74	9.88	26.60	46.22	64.00	17.78	Average
7	11.93	10.07	10.04	19.30	39.41	64.00	24.59	Average
8	11.93	10.07	10.04	36.60	56.71	74.00	17.29	QP
9	26.55	10.58	10.18	34.50	55.26	74.00	18.74	QP
10	26.55	10.58	10.18	15.90	36.66	64.00	27.34	Average
11	27.56	10.62	10.19	18.10	38.91	64.00	25.09	Average
12	27.56	10.62	10.19	35.60	56.41	74.00	17.59	QP

Remarks:  
 1. Emission Level= ISN factor + Cable loss + Reading .

## 5 RADIATED EMISSION TEST

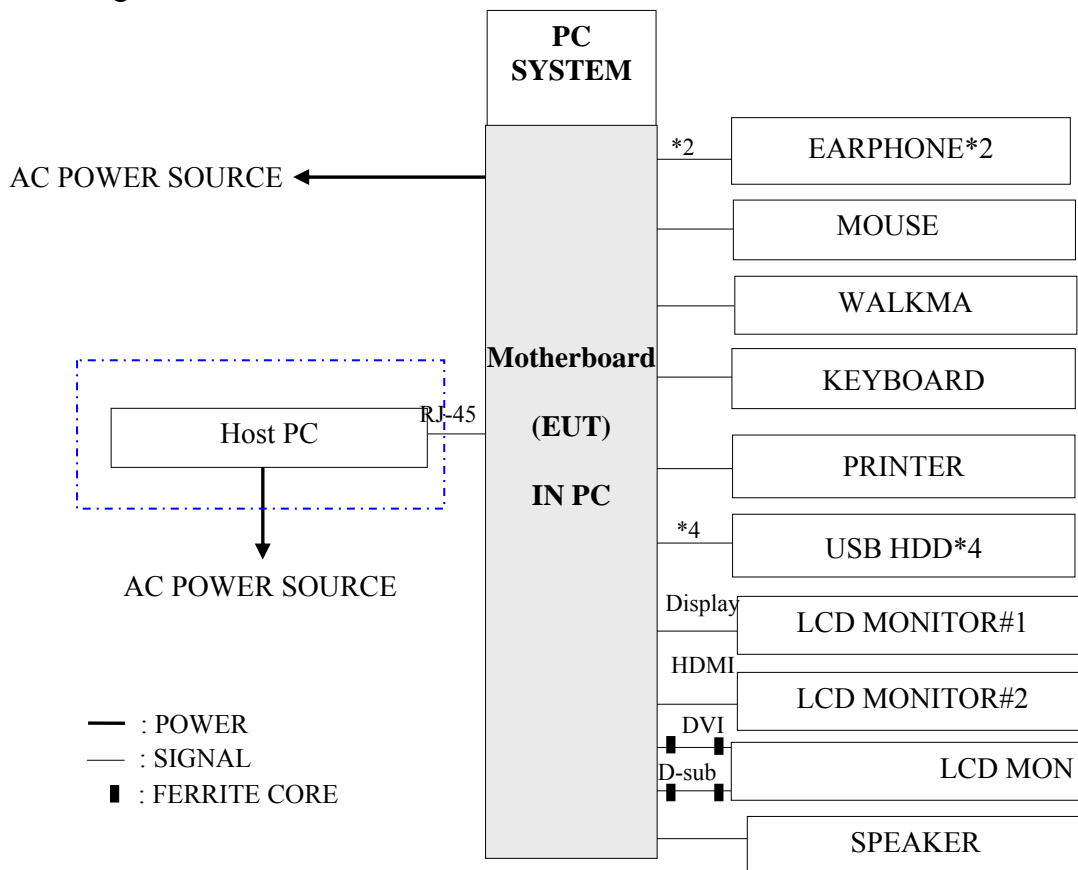
### 5.1 Test Equipment

The following test equipment was used during the radiated emission measurement  
(At 10m Semi-Anechoic Chamber)

Item	Type	Manufacturer	Model No.	Serial No.	Last Cal.	Next Cal.
1.	Spectrum Analyzer	Agilent	E7405A	MY45107028	2015-01-05	2016-01-04
2.	PXA signal analyzer	Agilent	N9030A	MY53120367	2015-06-23	2016-06-22
3.	Pre-Amplifier	Agilent	8447D	2944A10923	2015-07-03	2016-07-03
4.	Pre-Amplifier	Agilent	8447D	2944A10922	2015-07-03	2016-07-03
5.	Bi-log Antenna (Horizontal)	Schaffner	CBL6112D	22251	2015-05-20	2016-05-19
6.	Bi-log Antenna (Vertical)	Schaffner	CBL6112D	22252	2014-11-24	2015-11-23
7.	Horn Antenna	EMCO	3115	62959	2015-06-30	2016-06-29
8.	Test Receiver	R&S	ESCI	100839	2015-01-05	2016-01-04
9.	RF SWITCH	AUDIX	R2S	20121102111250	2015-01-05	2016-01-04
10.	Microwave amplifier	Agilent	8449B	3008A02234	2015-01-05	2016-01-04
11.	RF Cable	Yuhang	CSRH	001	2015-01-05	2016-01-04
12.	RF Cable	Yuhang	CSRH	002	2015-01-05	2016-01-04
13.	RF Cable	Yuhang	CSRH	003	2015-01-05	2016-01-04
14.	RF Cable	Yuhang	CSRH	004	2015-01-05	2016-01-04
15.	RF Cable	Yuhang	CSRH	005	2015-01-05	2016-01-04
16.	RF Cable	Yuhang	CSRH	006	2015-01-05	2016-01-04
17.	RF Cable	Yuhang	CSRH	008	2015-01-05	2016-01-04
18.	RF Cable	Yuhang	CSRH	009	2015-01-05	2016-01-04
19.	RF Cable	Huber+Suhner	SUCOFLEX 102	28571	2015-01-05	2016-01-04
20.	RF Cable	Huber+Suhner	SUCOFLEX 102	28579	2015-01-05	2016-01-04
21.	Software	Audix/e3(6.7.0313)				

5.2 Block Diagram of Test Setup

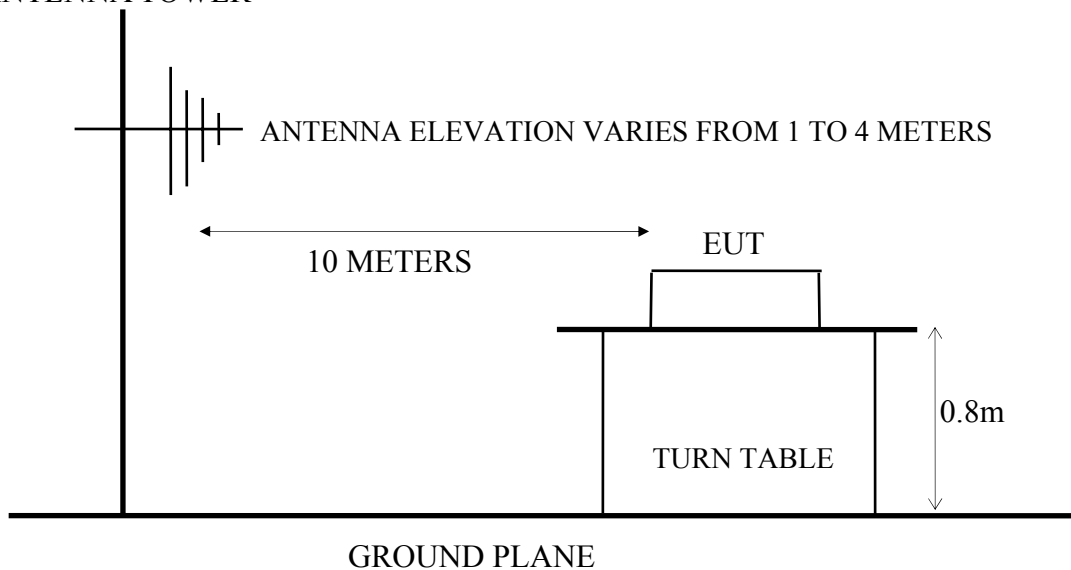
5.2.1 Block Diagram of connection between EUT and simulators



5.2.2 No. 1 10m Semi-Anechoic Chamber Setup Diagram (Test distance: 10m)

For Below 1G

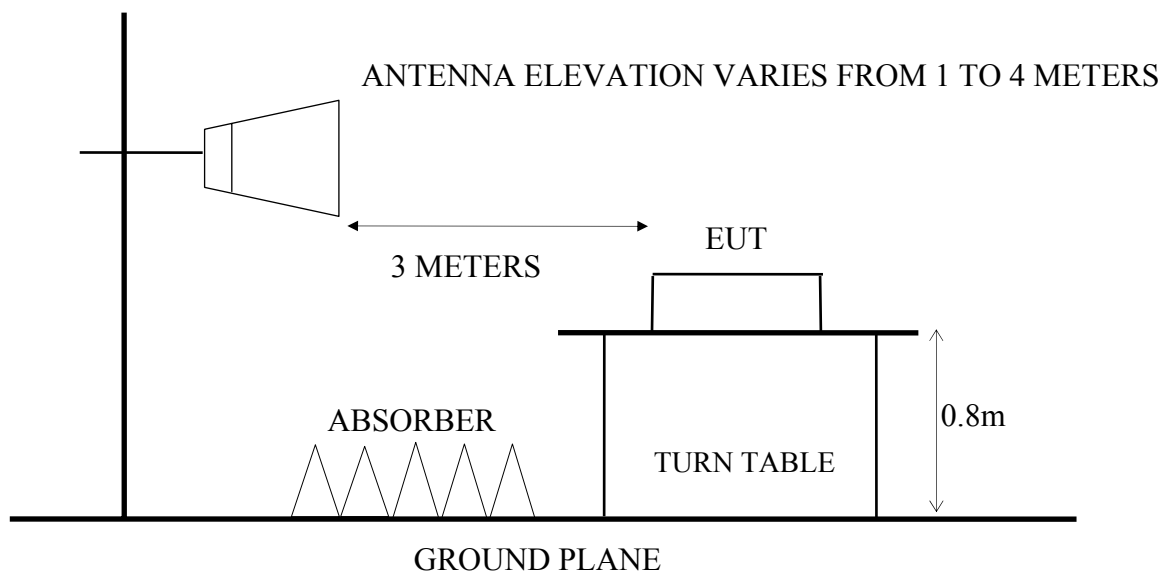
ANTENNA TOWER



## 5.2.3 No. 1 10m Semi-Anechoic Chamber Setup Diagram (Test distance: 3m)

**For Above 1GHz**

ANTENNA TOWER



## 5.3 Limits for Radiated Emission

ETSI EN 301 489-1 V1.8.1/2008, Sub clause 8.2 (EN 55022, Class B)

FREQUENCY (MHz)	DISTANCE (Meters)	Field Strengths Limits
30 ~ 230	10	30(dB $\mu$ V/m)
230 ~ 1000	10	37(dB $\mu$ V/m)
1000~ 3000	3	AV 50(dB $\mu$ V/m)
		PEAK 70(dB $\mu$ V/m)
3000~ 6000	3	AV 54(dB $\mu$ V/m)
		PEAK 74(dB $\mu$ V/m)

Note : (1) The tighter limit shall apply at the edge between two frequency bands.

(2) Distance refers to the distance in meters between the measuring instrument antenna and the closed point of any part of the EUT



#### 5.4 Test Procedure

The measuring process is according to ETSI EN 301 489-1 V1.9.2 (EN 55022) and laboratory internal procedure TKC-301-001.

In the radiated disturbance measurement, the EUT and all simulators were set up on a non-metallic turn table which was 0.8 meter above the ground plane. Measurement distance between EUT and receiving antennas was set at 10 meters at 30MHz~1GHz and 3 meters at 1GHz~6GHz. The measurement distance is the shortest horizontal distance between an imaginary circular periphery which consist of EUT periphery and cables and the reference point of the antenna. During the radiated measurement, the EUT was rotated 360° and receiving antennas were moved from 1 ~ 4 meters for finding maximum emission. Two receiving antennas were used for both horizontal and vertical polarization detection for 30MHz~1GHz, One receiving antennas was used for both horizontal and vertical polarization detection for 1GHz~6GHz (the absorbing material was added when testing of 1GHz~6GHz was done). All cables or wires placement were verified to find out the maximum emission.

The bandwidth of measuring receiver (or spectrum analyzer) was set to:

RBW (120 kHz), VBW (1MHz) for QP detector below 1GHz

RBW (1 MHz), VBW (1MHz) for Peak detector above 1GHz

RBW (1 MHz), VBW (10 Hz) for Average detector above 1GHz

which is defined against CISPR16-1-1 6.4.3 section.

The required frequency band (30 MHz ~ 6GHz)) was pre-scanned with peak detector; all final measurements were measured with quasi-peak detector below 1GHz, measured with average detector and peak detector above 1GHz.

The emission level is calculated automatically by the test system which uses the following equation:

1. For 30MHz~1GHz measurement:

$$\text{Emission Level (dB}\mu\text{V/m)} = \text{Reading (dB}\mu\text{V)} + \text{Antenna Factor (dB/m)} + \text{Cable Loss (dB)}$$

2. For 1GHz~6GHz measurement:

$$\text{Emission Level (dB}\mu\text{V/m)} = \text{Reading (dB}\mu\text{V)} + \text{Antenna Factor (dB/m)} + \text{Cable Loss (dB)} \\ - \text{Pre-amplifier factor (dB)}$$

In chapter 7.6.6.1 the standard EN 55016-2-3 requires to include the values of w in the test report:

“w: The dimension of the line tangent to the EUT formed by  $\Theta$ 3dB at the measurement distance d.

Equation (10) shall be used to calculate w for each actual antenna and measurement distance used.

The values of w shall be included in the test report. This calculation may be based on the

manufacturer-provided receive-antenna beamwidth specifications:

$$w = 2 \times d \times \tan(0,5 \times \Theta_{3\text{dB}})$$

Frequency GHz	3115 Horn	
	$\Theta_{3\text{dB}}$ (°)	d=3m w (M)
1.00	66	3.90
2.00	54	3.06
4.00	50	2.80
6.00	34	1.83

The values of w. are greater than chapter 7.6.6.1 of Table 2, the minimum dimension of w. (Wmin) requirements.

## 5.5 Measurement Results

**PASSED.**

EUT with the following were performed during the test and all the test results are listed in next pages.

## 5.5.1 For 30MHz~1GHz

Test Date: Aug, 25, 2015

Temperature: 21.4

Humidity: 63 %

Item	Test Mode	Reference Test Data No.	
		Horizontal	Vertical
1	WLAN+ BT Operating	# 11	# 12

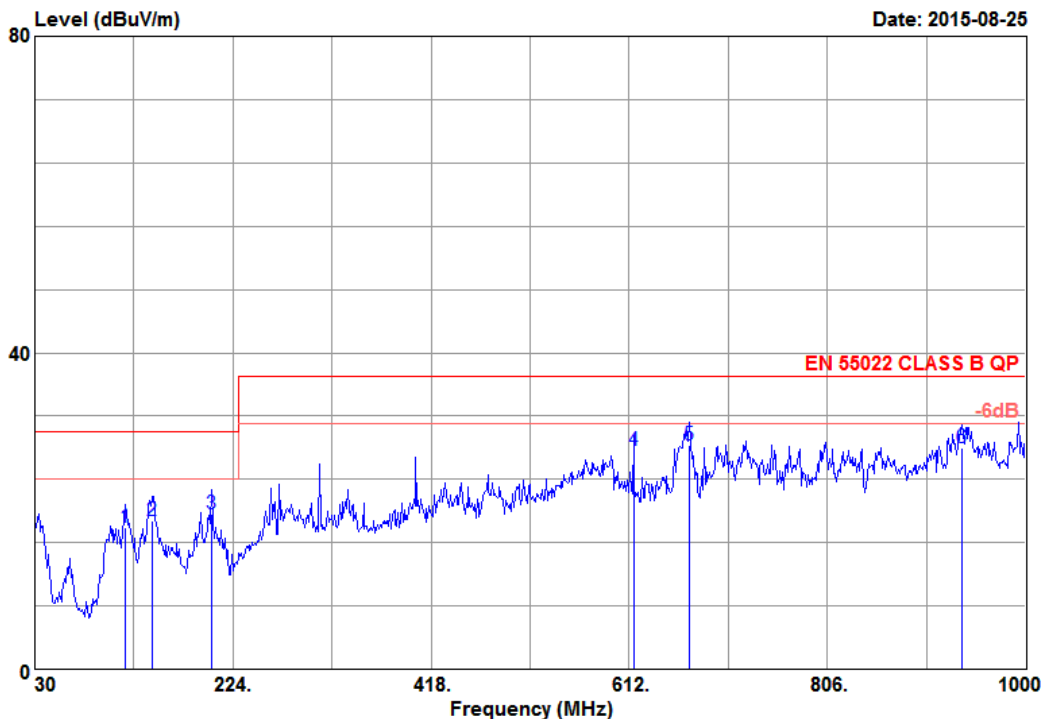
NOTE 1 - 0° was the table front facing the antenna. Degree is calculated from 0° clockwise facing the antenna.

NOTE 2 - The worst emission at horizontal polarization was detected at 671.16 MHz with emission level of 28.27 dB $\mu$ V/m (limit is 37.00 dB $\mu$ V/m), when the antenna was 3.1 m height and the turntable was at 192°. The worst emission at vertical polarization was detected at 183.27 MHz with emission level of 23.43 dB $\mu$ V/m (limit is 30.00 dB $\mu$ V/m), when the antenna was 1.0 m height and the turntable was at 210°.



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Data: 11 File: G:\TEST DATA\2015\Report\08\G1508022.EM6 (22)



Site No. : NO.1 10m Semi-Anechoic Chamber Data NO. : 11  
 Dis./Ant. : 10m . 6112D(50)-1409-H-10M Ant.pol : HORIZONTAL  
 Env./Ins. : 21.4\*C 63%/ESCI Engineer : Frank  
 EUT. : Motherboard  
 M/N : H170I-PLUS D3  
 Power Rating: 230Vac/50Hz  
 Test Mode : WLAN+BT Operating  
 Memo : Intel(R) Core(TM) i5-6400 CPU@ 2.70GHz  
 BIOS:0302

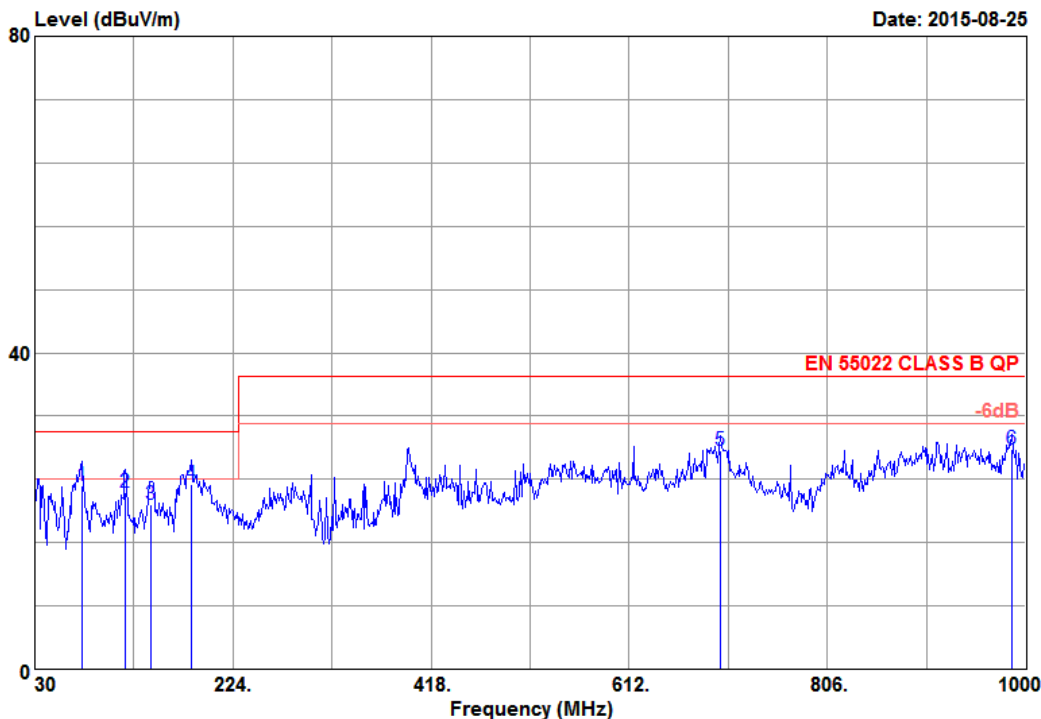
	Freq. (MHz)	Ant. Factor (dB)	Cable Loss (dB)	Reading (dBuV)	Emission Level (dBuV/m)	Limits (dBuV/m)	Margin (dB)	Remark
1	118.92	12.25	2.00	3.65	17.90	30.00	12.10	QP
2	144.66	11.00	2.24	5.56	18.80	30.00	11.20	QP
3	203.16	9.10	2.65	7.87	19.62	30.00	10.38	QP
4	616.17	18.94	4.86	3.77	27.57	37.00	9.43	QP
5	671.16	19.00	5.08	4.19	28.27	37.00	8.73	QP
6	937.92	21.00	6.08	0.82	27.90	37.00	9.10	QP

Remarks: 1.Emission Level= Antenna factor + Cable loss + Reading  
 2.The emission level that are 20dB below the official limit are not reported



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Data: 12 File: G:\TEST DATA\2015\Report\08\G1508022.EM6 (22)



Site No. : NO.1 10m Semi-Anechoic Chamber Data NO. : 12  
 Dis./Ant. : 10m . 6112D(52)-1411-V-10M Ant.pol : VERTICAL  
 Env./Ins. : 21.4\*C 63%/ESCI Engineer : Frank  
 EUT. : Motherboard  
 M/N : H170I-PLUS D3  
 Power Rating: 230Vac/50Hz  
 Test Mode : WLAN+BT Operating  
 Memo : Intel(R) Core(TM) i5-6400 CPU@ 2.70GHz  
 BIOS:0302

	Freq. (MHz)	Ant. Factor (dB)	Cable Loss (dB)	Reading (dBuV)	Emission Level (dBuV/m)	Limits (dBuV/m)	Margin (dB)	Remark
1	75.63	7.70	1.25	14.27	23.22	30.00	6.78	QP
2	118.92	12.40	1.61	8.29	22.30	30.00	7.70	QP
3	143.49	11.50	1.79	7.49	20.78	30.00	9.22	QP
4	183.27	10.00	2.02	11.41	23.43	30.00	6.57	QP
5	701.58	19.83	4.24	3.53	27.60	37.00	9.40	QP
6	987.06	22.40	5.06	0.29	27.75	37.00	9.25	QP

Remarks: 1.Emission Level= Antenna factor + Cable loss + Reading  
 2.The emission level that are 20dB below the official limit are not reported

## 5.5.2 For 1GHz~6GHz

Test Date: Aug.25,2015

Temperature:21.4

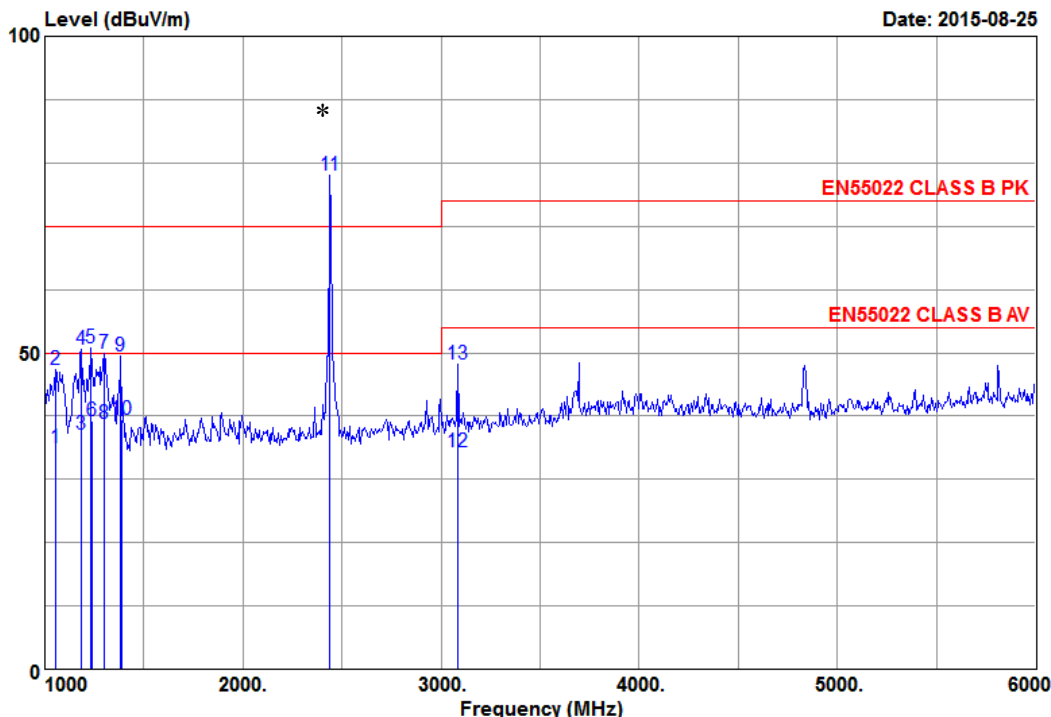
Humidity: 63%

Item	Test Mode	Reference Test Data No.	
		Horizontal	Vertical
1	Full System (WLAN+ BT Operating)	# 43	# 44



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Data: 21 File: G:\TEST DATA\2015\Report\08\G1508022.EM6 (22)



Site No. : NO.1 10m Semi-Anechoic Chamber Data NO. : 21  
 Dis./Ant. : 3m . 3115-62960-150630 Ant.pol : HORIZONTAL  
 Limit : EN55022 CLASS B PK  
 Env./Ins. : 21.4\*C 63%N9030A Engineer : Frank  
 EUT. : Motherboard  
 M/N : H170I-PLUS D3  
 Power Rating : 230Vac/50Hz  
 Test Mode : WLAN+BT Operating  
 Memo : Intel(R) Core(TM) i5-6400 CPU@ 2.70GHz  
 BIOS:0302

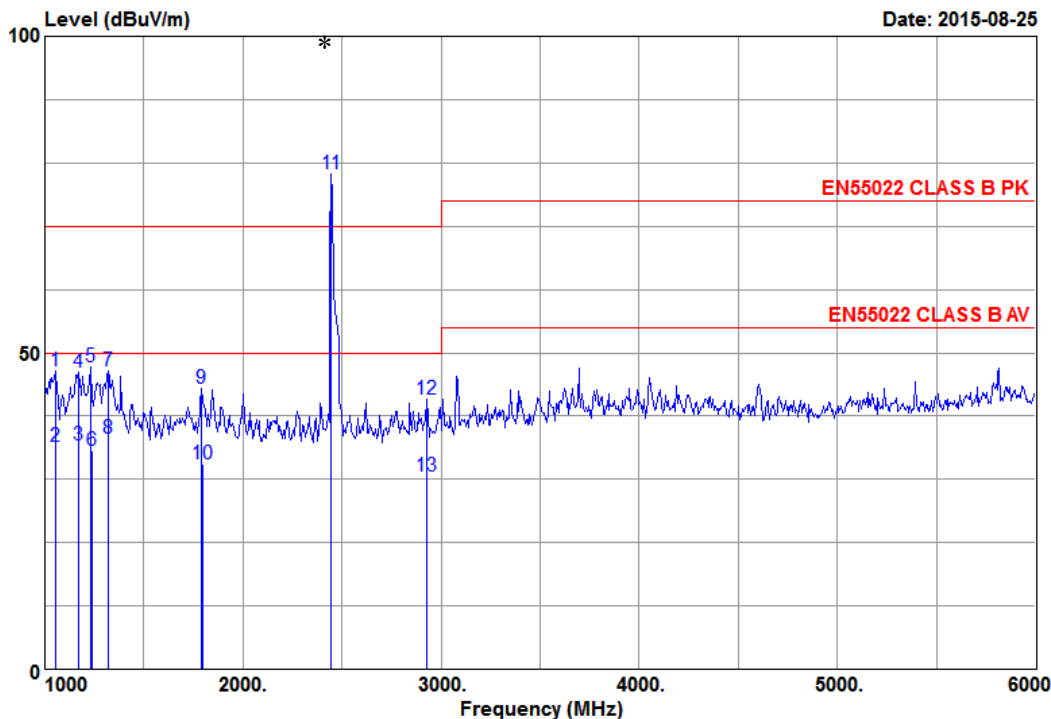
	Freq. (MHz)	Ant. Factor (dB)	Cable Loss (dB)	Reading (dBuV)	Preamp Factor (dB)	Emission Level (dBuV/m)	Limits (dBuV/m)	Margin (dB)	Remark
1	1053.00	23.48	3.24	44.20	35.98	34.94	50.00	15.06	Average
2	1054.00	23.48	3.24	56.50	35.98	47.24	70.00	22.76	Peak
3	1184.50	23.94	3.43	45.61	35.85	37.13	50.00	12.87	Average
4	1186.00	23.94	3.43	59.13	35.85	50.65	70.00	19.35	Peak
5	1234.00	24.12	3.51	58.82	35.79	50.66	70.00	19.34	Peak
6	1237.00	24.12	3.51	47.30	35.79	39.14	50.00	10.86	Average
7	1300.00	24.36	3.62	57.71	35.71	49.98	70.00	20.02	Peak
8	1302.00	24.36	3.62	46.50	35.71	38.77	50.00	11.23	Average
9	1384.00	24.65	3.74	56.61	35.63	49.37	70.00	20.63	Peak
10	1385.00	24.65	3.74	46.80	35.63	39.56	50.00	10.44	Average
11	2440.00	28.58	5.12	79.49	35.16	78.03	70.00	-8.03	Peak *
12	3081.40	30.27	5.84	33.50	35.29	34.32	54.00	19.68	Average
13	3082.00	30.27	5.84	47.39	35.29	48.21	74.00	25.79	Peak

Remarks: 1.Emission Level= Antenna factor + Cable loss + Reading - Preamp  
 2.The emission level that are 20dB below the official limit are not reported  
 3. "\*" is the fundamental frequency emission emanating from the intentional radio components such as WLAN module.  
 It could be ignored in this report according to ETSI EN301489-1.



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Data: 22 File: G:\TEST DATA\2015\Report\08\G1508022.EM6 (22)



Site No. : NO.1 10m Semi-Anechoic Chamber Data NO. : 22  
 Dis./Ant. : 3m . 3115-62960-150630 Ant.pol : VERTICAL  
 Limit : EN55022 CLASS B PK  
 Env./Ins. : 21.4\*C 63%N9030A Engineer : Frank  
 EUT. : Motherboard  
 M/N : H170I-PLUS D3  
 Power Rating : 230Vac/50Hz  
 Test Mode : WLAN+BT Operating  
 Memo : Intel(R) Core(TM) i5-6400 CPU@ 2.70GHz  
 BIOS:0302

	Freq. (MHz)	Ant. Factor (dB)	Cable Loss (dB)	Reading (dBuV)	Preamp Factor (dB)	Emission Level (dBuV/m)	Limits (dBuV/m)	Margin (dB)	Remark
1	1054.00	23.48	3.24	56.47	35.98	47.21	70.00	22.79	Peak
2	1055.00	23.48	3.24	44.50	35.98	35.24	50.00	14.76	Average
3	1167.50	23.89	3.43	43.90	35.85	35.37	50.00	14.63	Average
4	1168.00	23.89	3.43	55.54	35.85	47.01	70.00	22.99	Peak
5	1234.00	24.12	3.51	55.95	35.79	47.79	70.00	22.21	Peak
6	1236.00	24.12	3.51	42.70	35.79	34.54	50.00	15.46	Average
7	1318.00	24.41	3.62	54.90	35.71	47.22	70.00	22.78	Peak
8	1319.00	24.41	3.66	44.11	35.69	36.49	50.00	13.51	Average
9	1792.00	26.50	4.36	48.69	35.21	44.34	70.00	25.66	Peak
10	1795.00	26.50	4.36	36.80	35.21	32.45	50.00	17.55	Average
11	2446.00	28.58	5.15	79.80	35.17	78.36	70.00	-8.36	Peak *
12	2926.00	29.87	5.66	42.55	35.34	42.74	70.00	27.26	Peak
13	2928.00	29.87	5.66	30.39	35.34	30.58	50.00	19.42	Average

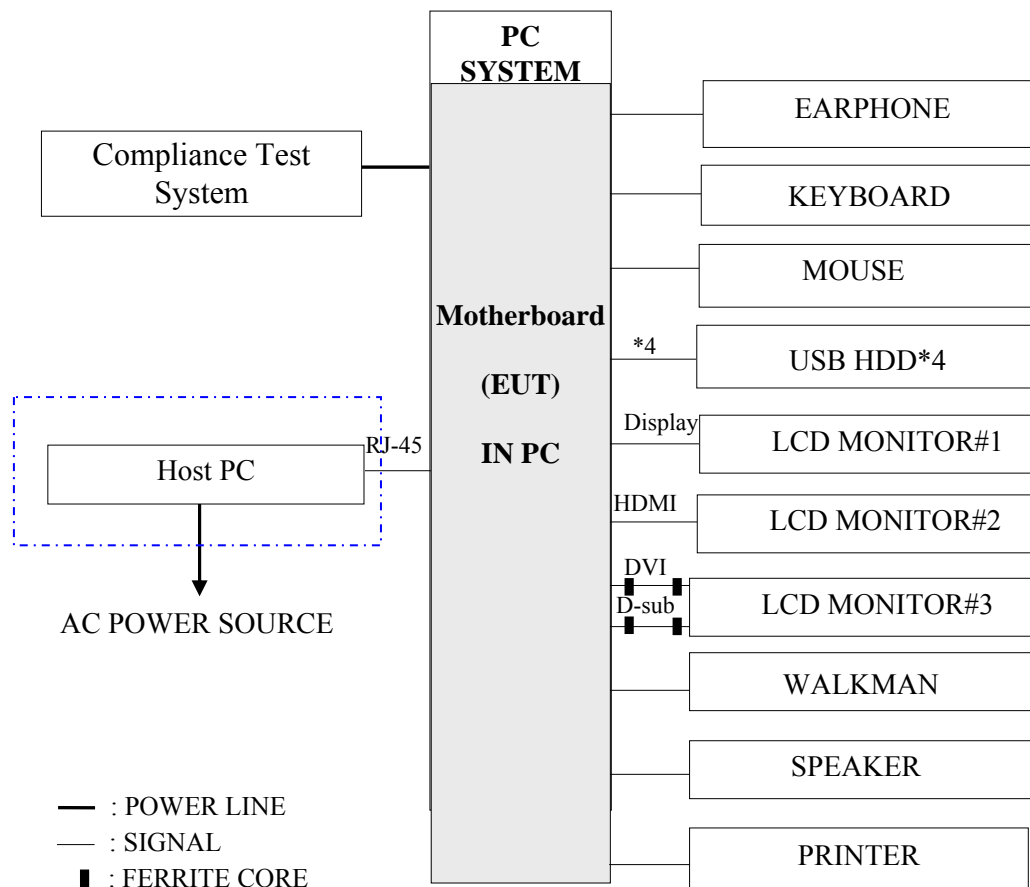
Remarks: 1.Emission Level= Antenna factor + Cable loss + Reading - Preamp  
 2.The emission level that are 20dB below the official limit are not reported  
 3. "\*" is the fundamental frequency emission emanating from the intentional radio components such as WLAN module. It could be

## 6 POWER HARMONICS AND FLICKER MEASUREMENT TEST EQUIPMENT

### 6.1 Test Equipment

Item	Type	Manufacturer	Model No.	Serial No.	Last Cal.	Next Cal.
1.	AC power source	TESEQ	NSG1007-45-3PI	1236A00705	2015-09-17	2017-09-16
2.	Signal Conditioning Unit	TESEQ	CCN1000-3	1236A00705	2015-09-17	2017-09-16
3.	Threephase Impedance network	TESEQ	INA2197	1236A00705	2015-09-17	2017-09-16

### 6.2 Block Diagram of Test Setup





## 6.3 Test Standard

ETSI EN 301 489-1 V1.9.2:2011-09, Sub clause 8.5&8.6  
(EN 61000-3-2:2014 & EN 61000-3-3:2013)

## 6.4 Test Procedure

The measuring process is according to EN61000-3-2:2014&  
EN 61000-3-3:2013 and laboratory internal procedure TKC-301-012.

## 6.5 Test Results

6.5.1 The limits for Class D equipment are valid for all applications having an active input power is >75W, due to the EUT measured active input power is <75W, therefore, no limits apply for this equipment according to EN 61000-3-2.

6.5.2 PASSED. (complied with Class D limit)

EUT with the following test mode was measured during this section testing and all the test results are listed in next page.

Test Date: Aug.21, 2015

Temperature: 23.8

Humidity: 62%

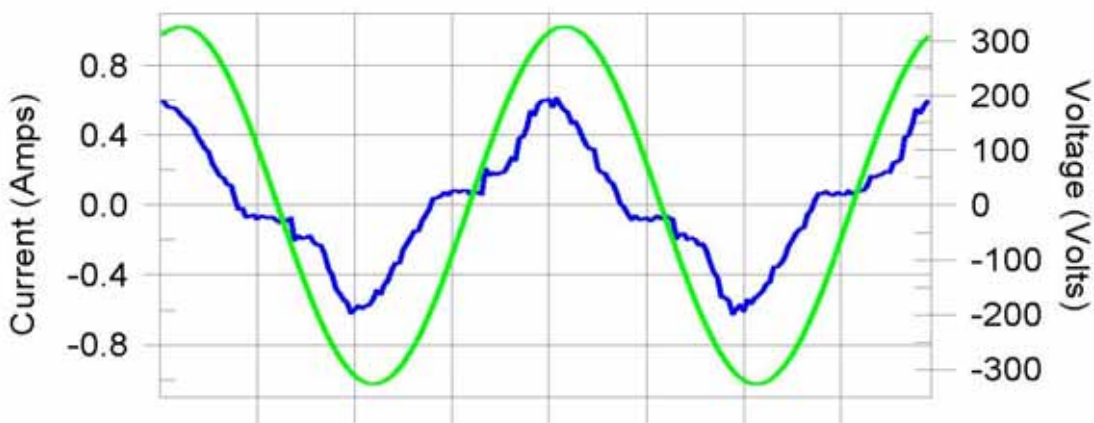
Item	Test Condition
1	WLAN+BT Operating

**Harmonics – Class-D per Ed. 4.0 (2014)(Run time)**

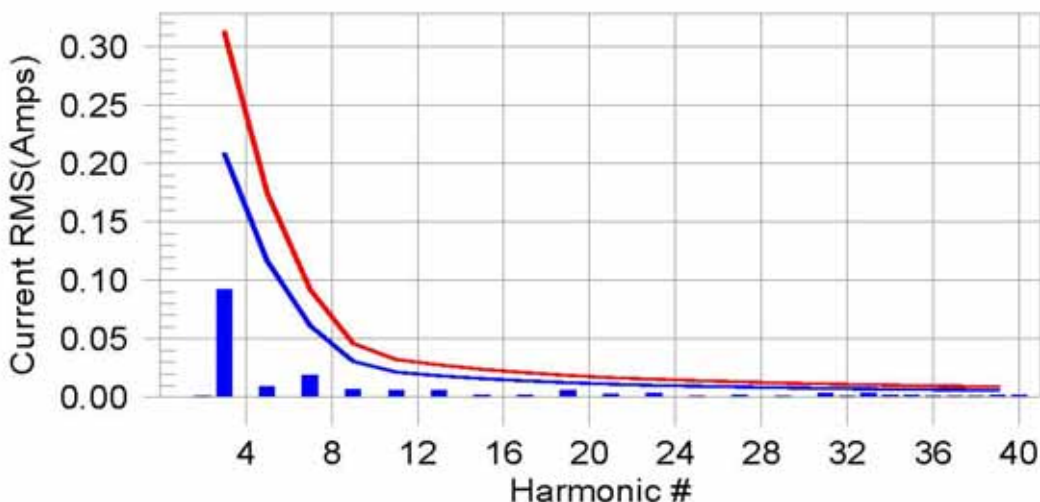
**EUT: Motherboard** **Tested by: Puck**  
**Test category: Class-D per Ed. 4.0 (2014) (Japanese limits)** **Test Margin: 100**  
**Test date: 2015-8-21**  
**Test duration (min): 5** **Data file name: WIN2105\_H-000093.cts\_data**  
**Comment: M/N: H170I-PLUS D3 Test Mode: WLAN+BT Operating**  
**Customer: ASUSTeK COMPUTER INC.**

**Test Result: N/L** **Source qualification: Normal**

**Current & voltage waveforms**



**Harmonics and Class D limit line** **Japanese Limits**



**Test result: N/L** **Worst harmonic was #19 with 45.4% of the limit.**

Teseq Proflin  
4542 Luterbach, Switzerland

10/8/2015  
5:22:17 PM

### Current Test Result Summary (Run time)

EUT: Motherboard Tested by: Puck  
 Test category: Class-D per Ed. 4.0 (2014) (Japanese limits) Test Margin: 100  
 Test date: 2015-8-21  
 Test duration (min): 5 Data file name: WIN2105\_H-000093.cts\_data  
 Comment: M/N: H170I-PLUS D3 Test Mode: Full System(HDMI+DP 2560\*1600@60Hz)  
 Customer: ASUSTeK COMPUTER INC.

Test Result: N/L Source qualification: Normal  
 THC: 0.000 A I-THD: 0.0 % POHC(A): 0.000 A POHC Limit(A): 0.000 A  
 Highest parameter values during test:

V_RMS (Volts):	230.712	Frequency(Hz):	50.00
I_Peak (Amps):	0.644	I_RMS (Amps):	0.299
I_Fund (Amps):	0.281	Crest Factor:	2.120
Power (Watts):	61.3	Power Factor:	0.896

Harm#	Harms(avg)	100%Limit	%of Limit	Harms(max)	150%Limit	%of Limit	Status
2	0.001	0.000	N/A	0.002	0.000	N/A	Pass
3	0.092	0.208	N/A	0.096	0.313	N/A	Pass
4	0.001	0.000	N/A	0.001	0.000	N/A	Pass
5	0.009	0.116	N/A	0.010	0.175	N/A	Pass
6	0.000	0.000	N/A	0.000	0.000	N/A	Pass
7	0.019	0.061	N/A	0.020	0.092	N/A	Pass
8	0.000	0.000	N/A	0.000	0.000	N/A	Pass
9	0.007	0.031	N/A	0.008	0.046	N/A	Pass
10	0.000	0.000	N/A	0.000	0.000	N/A	Pass
11	0.006	0.021	N/A	0.007	0.032	N/A	Pass
12	0.000	0.000	N/A	0.000	0.000	N/A	Pass
13	0.006	0.018	N/A	0.006	0.028	N/A	Pass
14	0.000	0.000	N/A	0.000	0.000	N/A	Pass
15	0.002	0.016	N/A	0.003	0.024	N/A	Pass
16	0.000	0.000	N/A	0.000	0.000	N/A	Pass
17	0.002	0.014	N/A	0.003	0.021	N/A	Pass
18	0.000	0.000	N/A	0.000	0.000	N/A	Pass
19	0.006	0.012	N/A	0.006	0.019	N/A	Pass
20	0.000	0.000	N/A	0.000	0.000	N/A	Pass
21	0.003	0.011	N/A	0.004	0.017	N/A	Pass
22	0.000	0.000	N/A	0.000	0.000	N/A	Pass
23	0.003	0.010	N/A	0.003	0.015	N/A	Pass
24	0.000	0.000	N/A	0.000	0.000	N/A	Pass
25	0.001	0.009	N/A	0.002	0.014	N/A	Pass
26	0.000	0.000	N/A	0.000	0.000	N/A	Pass
27	0.002	0.009	N/A	0.002	0.013	N/A	Pass
28	0.000	0.000	N/A	0.000	0.000	N/A	Pass
29	0.001	0.008	N/A	0.002	0.012	N/A	Pass
30	0.000	0.000	N/A	0.000	0.000	N/A	Pass
31	0.004	0.008	N/A	0.004	0.011	N/A	Pass
32	0.001	0.000	N/A	0.002	0.000	N/A	Pass
33	0.003	0.007	N/A	0.004	0.011	N/A	Pass
34	0.002	0.000	N/A	0.004	0.000	N/A	Pass
35	0.002	0.007	N/A	0.003	0.010	N/A	Pass
36	0.001	0.000	N/A	0.002	0.000	N/A	Pass
37	0.001	0.006	N/A	0.002	0.010	N/A	Pass
38	0.001	0.000	N/A	0.002	0.000	N/A	Pass
39	0.002	0.006	N/A	0.003	0.009	N/A	Pass
40	0.002	0.000	N/A	0.004	0.000	N/A	Pass

Note: The EUT power level is below 75.0 Watts and therefore has no defined limits

Teseq Proflin  
4542 Luterbach, Switzerland

10/8/2015  
5:22:17 PM

### Voltage Source Verification Data (Run time)

EUT: Motherboard Tested by: Puck  
 Test category: Class-D per Ed. 4.0 (2014) (Japanese limits) Test Margin: 100  
 Test date: 2015-8-21  
 Test duration (min): 5 Data file name: WIN2105\_H-000093.cts\_data  
 Comment: M/N: H170I-PLUS D3 Test Mode: Full System(HDMI+DP 2560\*1600@60Hz)  
 Customer: ASUSTeK COMPUTER INC.

Test Result: N/L Source qualification: Normal

#### Highest parameter values during test:

Voltage (Vrms):	230.712	Frequency(Hz):	50.00
I_Peak (Amps):	0.644	I_RMS (Amps):	0.299
I_Fund (Amps):	0.281	Crest Factor:	2.120
Power (Watts):	61.3	Power Factor:	0.896

Harm#	Harmonics V-rms	Limit V-rms	% of Limit	Status
2	0.094	0.461	20.29	OK
3	0.106	2.076	5.13	OK
4	0.031	0.461	6.78	OK
5	0.057	0.923	6.13	OK
6	0.014	0.461	3.10	OK
7	0.042	0.692	6.00	OK
8	0.015	0.461	3.25	OK
9	0.035	0.461	7.53	OK
10	0.016	0.461	3.39	OK
11	0.028	0.231	12.28	OK
12	0.010	0.231	4.21	OK
13	0.017	0.231	7.35	OK
14	0.009	0.231	3.93	OK
15	0.017	0.231	7.16	OK
16	0.007	0.231	3.03	OK
17	0.011	0.231	4.80	OK
18	0.005	0.231	2.21	OK
19	0.012	0.231	5.01	OK
20	0.011	0.231	4.57	OK
21	0.012	0.231	5.14	OK
22	0.007	0.231	3.18	OK
23	0.017	0.231	7.30	OK
24	0.007	0.231	2.83	OK
25	0.014	0.231	5.94	OK
26	0.007	0.231	3.10	OK
27	0.011	0.231	4.66	OK
28	0.006	0.231	2.64	OK
29	0.008	0.231	3.39	OK
30	0.005	0.231	2.35	OK
31	0.017	0.231	7.46	OK
32	0.005	0.231	2.19	OK
33	0.012	0.231	5.32	OK
34	0.007	0.231	3.02	OK
35	0.012	0.231	5.33	OK
36	0.006	0.231	2.68	OK
37	0.009	0.231	4.03	OK
38	0.006	0.231	2.46	OK
39	0.011	0.231	4.72	OK
40	0.011	0.231	4.75	OK

Teseq Proflin  
4542 Luterbach, Switzerland

10/8/2015  
5:23:31 PM

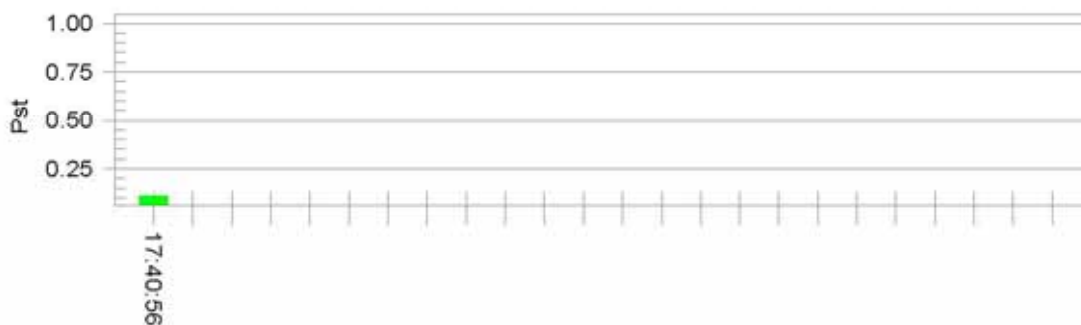
**Flicker Test Summary per EN/IEC61000-3-3 (Run time)**

**EUT: Motherboard** **Tested by: Puck**  
**Test category: dt,dmax,dc and Pst (European limits)** **Test Margin: 100**  
**Test date: 2015-8-21**  
**Test duration (min): 10** **Data file name: WIN2105\_F-000094.cts\_data**  
**Comment: M/N: H170I-PLUS D3 Test Mode: WLAN+BT Operating**  
**Customer: ASUSTeK COMPUTER INC.**

**Test Result: Pass** **Status: Test Completed**

**Pst and limit line**

**European Limits**



**Plt and limit line**



**Parameter values recorded during the test:**

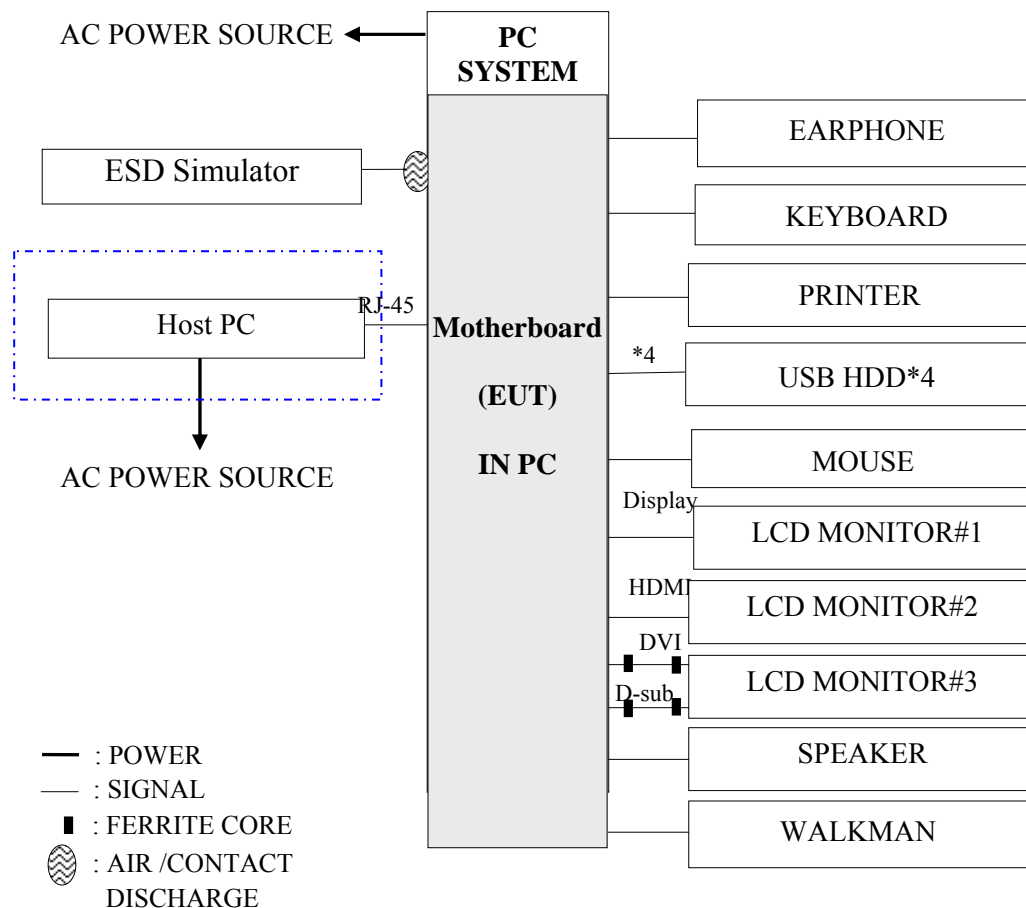
<b>Vrms at the end of test (Volt):</b>	<b>230.68</b>		
<b>Highest dt (%):</b>	<b>0.00</b>	<b>Test limit (%):</b>	<b>N/A N/A</b>
<b>T-max (mS):</b>	<b>0.0</b>	<b>Test limit (mS):</b>	<b>500.0 Pass</b>
<b>Highest dc (%):</b>	<b>0.00</b>	<b>Test limit (%):</b>	<b>3.30 Pass</b>
<b>Highest dmax (%):</b>	<b>0.04</b>	<b>Test limit (%):</b>	<b>4.00 Pass</b>
<b>Highest Pst (10 min. period):</b>	<b>0.108</b>	<b>Test limit:</b>	<b>1.000 Pass</b>

## 7 ELECTROSTATIC DISCHARGE IMMUNITY TEST

### 7.1 Test Equipment

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Next Cal.
1.	ESD SIMULATOR	NoiseKen	ESS-2000	ESS07X7519	2015-07-03	2016-07-03

### 7.2 Block Diagram of Test Setup



### 7.3 Test Standard

ETSI EN 301 489-1 V1.9.2:2011, Sub clause 9.3 (EN 61000-4-2:2009) & ETSI EN 301 489-17 V 2.2.1:2012

### 7.4 Test Levels and Performance Criteria

Test Level		Performance Criteria
Air Discharge	±2kV, ±4kV and ±8kV	<b>B</b>
Contact Discharge	±2kV and ±4kV	

## 7.5 Test Procedure

### 7.5.1 Air Discharge:

The test was applied on non-conductive surfaces of EUT. The round discharge tip of the discharge electrode was approached as fast as possible until contact the EUT. After each discharge, the discharge electrode was removed from the EUT. The generator was re-triggered for a new single discharge and repeated 20 times for each pre-selected test point. This procedure was repeated until all the air discharge completed

### 7.5.2 Contact Discharge:

All the procedure was same as Section 7.5.1. except that the generator was re-triggered for a new single discharge and repeated 50 times for each pre-selected test point. The tip of the discharge electrode was touching the EUT before the discharge switch was operated.

### 7.5.3 Indirect discharge for horizontal coupling plane

At least 20 single discharges were applied to the horizontal coupling plane, at points on each side of the EUT. The discharge electrode positions vertically at a distance of 0.1m from the EUT and with the discharge electrode touching the coupling plane.

### 7.5.4 Indirect discharge for vertical coupling plane

At least 20 single discharges were applied to the center of one vertical edge of the coupling plane. The coupling plane, of dimensions 0.5m X 0.5m, was placed parallel to, and positioned at a distance of 0.1m from the EUT. Discharges were applied to the coupling plane, with this plane in sufficient different positions that the four faces of the EUT are completely illuminated.

## 7.6 Test Results

**PASS.**

The details of test modes and reference test data are as follows:

## Electrostatic Discharge Immunity Test Results

<i>Applicant</i>	ASUSTeK COMPUTER INC.			<i>Date of Test</i>	2015.08.24		
<i>EUT</i>	Motherboard			<i>Power rating</i>	AC: 230 V ; 50 Hz		
<i>Model No.</i>	H170I-PLUS D3	<i>Temp.</i>	23.5	<i>Humidity</i>	45 %	<i>Atmosphere Pressure</i>	101kPa
<i>Test Mode</i>	WLAN+BT Operating						
<i>Working Condition</i>	Operating				<i>Results</i>	PASS	
<i>Item</i>	<i>Amount of Discharges</i>	<i>Discharge Voltage</i>				<i>Performance Criterion</i>	
<i>Contact Discharge</i>	1300	+ 2kV,+ 4kV				A	
		- 2kV, - 4kV				A	
<i>Air Discharge</i>	520	+ 2kV,+ 4kV,+ 8kV				A	
		- 2kV, - 4kV, - 8kV				A	
<i>Indirect Discharge (HCP)</i>	50	+ 2kV,+ 4kV				A	
		- 2kV, - 4kV				A	
<i>Indirect Discharge (VCP Front)</i>	50	+ 2kV,+ 4kV				A	
		- 2kV, - 4kV				A	
<i>Indirect Discharge (VCP Left)</i>	50	+ 2kV,+ 4kV				A	
		- 2kV, - 4kV				A	
<i>Indirect Discharge (VCP Back)</i>	50	+ 2kV,+ 4kV				A	
		- 2kV, - 4kV				A	
<i>Indirect Discharge (VCP Right)</i>	50	+ 2kV,+ 4kV				A	
		-2kV,-4kV				A	
<i>Test Points</i>	1.	Screw×4	Contact Discharge	2.	Metal×3	Contact Discharge	
	3.	Cover×5	Contact Discharge	4.	VGA	Contact/ Air Discharge	
	5.	Button×2	Air Discharge	6.	DVI	Contact/ Air Discharge	
	7.	USB×6	Contact/Air Discharge	8.	Line in	Air Discharge	
	9.	Line out	Air Discharge	10.	Mic in	Air Discharge	
	11.	Lan	Air Discharge	12.	SPDIF OUT	Contact/ Air Discharge	
	13.	DP	Contact/ Air Discharge	14.	AC IN	Air Discharge	
	15.	PS/2	Air Discharge	16.	ANT×2	Contact/ Air Discharge	
	17.	HDMI	Contact/ Air Discharge				



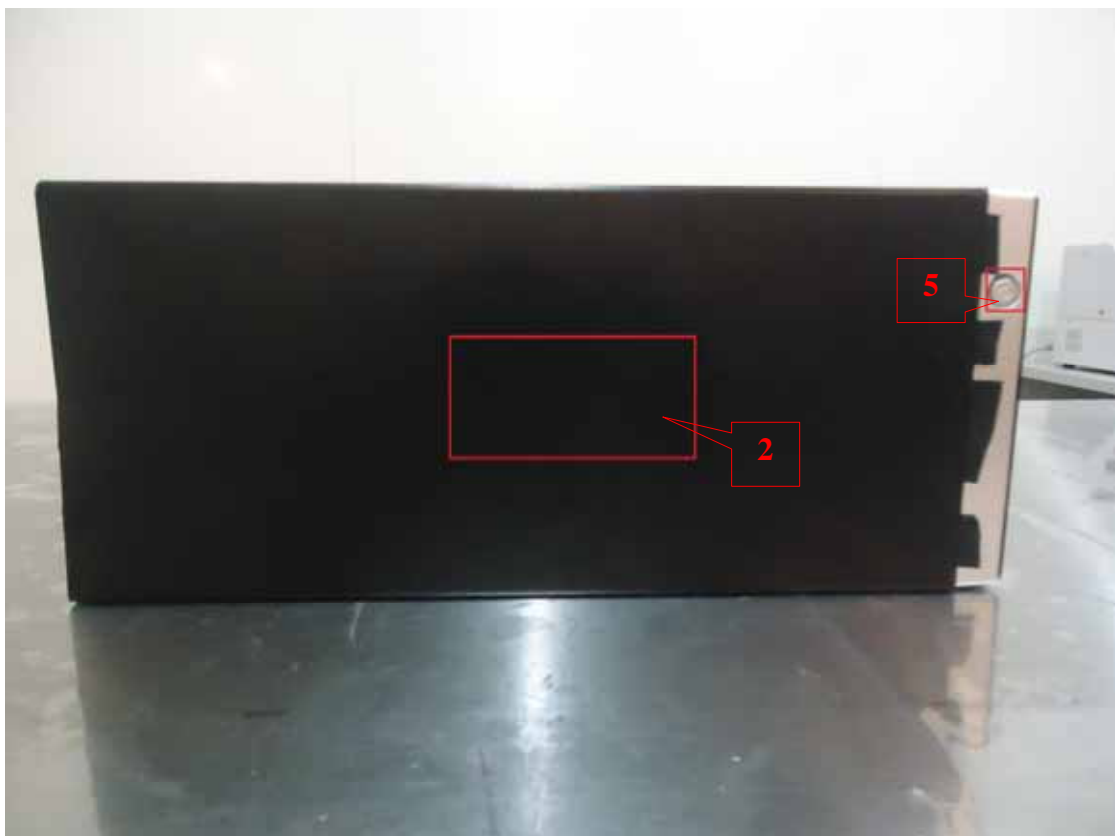
Note: IEC 61000-6-2

Engineer :Puck

Photos of Discharge Points:







## 8 RF FIELD STRENGTH SUSCEPTIBILITY TEST

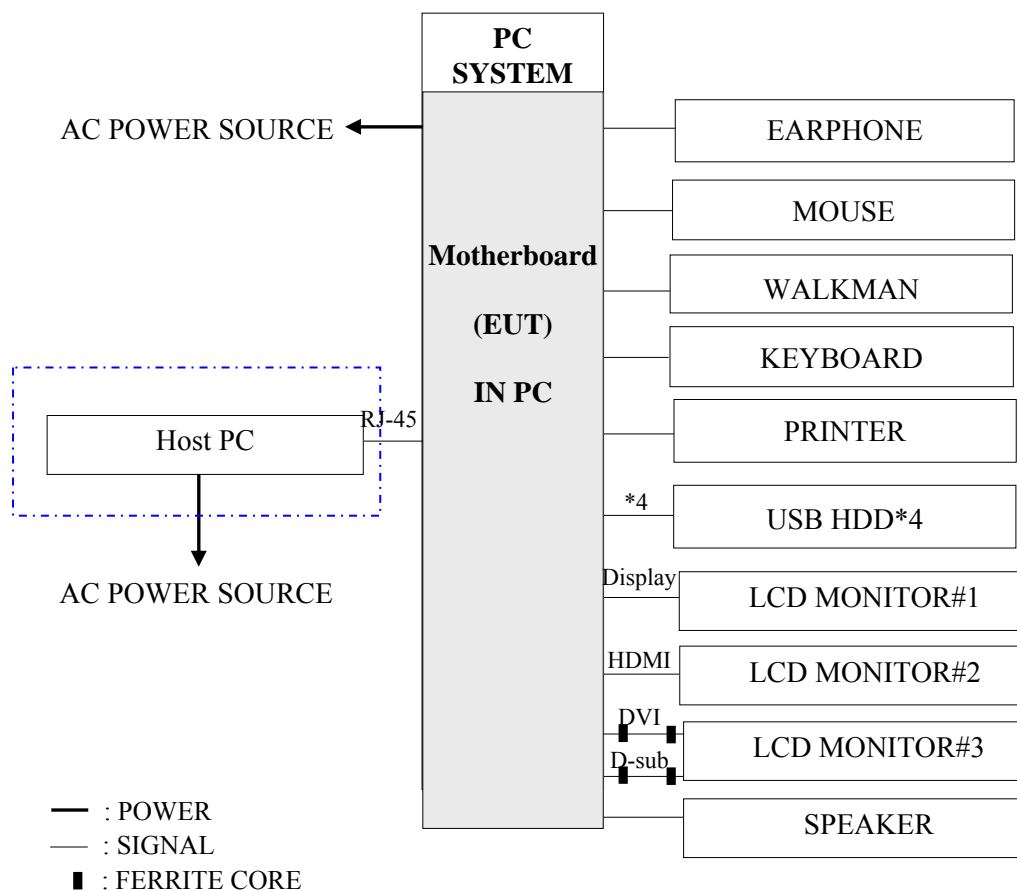
### 8.1 Test Equipment

Item	Type	Manufacturer	Model No.	Serial No.	Last Cal.	Next Cal.
1.	Signal Generator	Agilent	8648C	3847M01438	2015-01-05	2016-01-04
2.	Dual Band Power Amplifier	AR	KAW 2180	10088-2	NCR	NCR
3.	Power Sensor	Agilent	8481D	MY41093045	2015-01-05	2016-01-04
4.	Dual Channel EPM Series Power Meter	Agilent	E4419B	MY45100928	2015-01-05	2016-01-04
5.	Log-Periodic Antenna	AR	AT1080	0323131	NCR	NCR
6.	Dual directional coupler	AR	DC6180A	322333	2015-07-03	2016-07-03
7.	Dual directional coupler	AR	DC7144A	322193	2015-07-03	2016-07-03
8.	Software	Audix/i2(4.110314)				

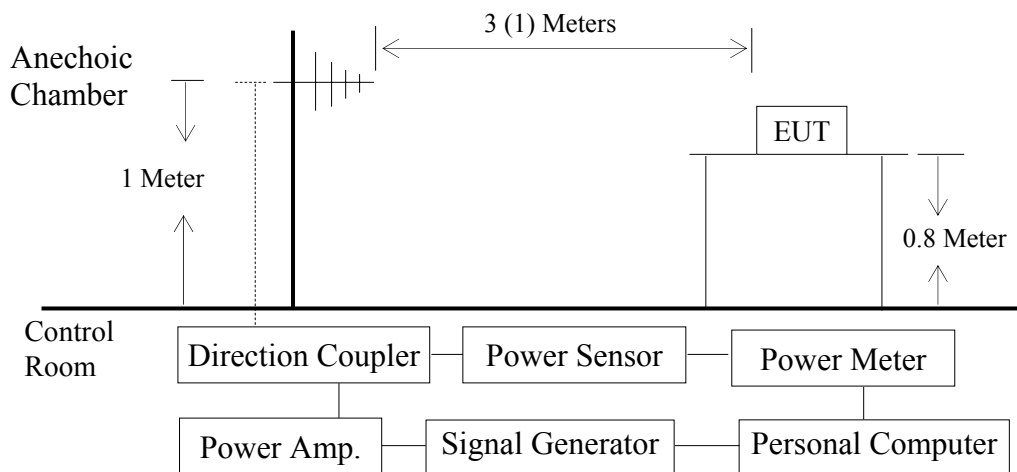
NCR: Non-Calibration Requirement.

8.2 Block Diagram of Test Setup

8.2.1 Block Diagram of connection between EUT and simulators.



8.2.2 R/S Test Setup



8.3 Test Standard

ETSI EN 301 489-1 V1.9.2:2011-09, clause 9.2 (EN 61000-4-3:2006+A2:2010) & ETSI EN 301 489-17 V2.2.1:2012-09

8.4 Test Levels and Performance Criteria

Test Level		Performance Criteria
Frequency	80MHz-1GHz, 1.4GHz-2.7GHz	▲

Field Strength	3V/m	
Modulation & Signal	80%, 1kHz	

#### 8.5 Exclusion bands

The frequency on which the transmitter part of the EUT is intended to operate shall be excluded from conducted and radiated emission measurements when performed in transmit mode of operation.

The exclusion band for the transmitter and/or receiver part of the 2.45GHz WLAN equipment under test shall extend from 2280MHz to 2607.675MHz

#### 8.6 Test Procedure

The field sensor is placed on the EUT table (0.8 meter above the ground) which is 3 meters for frequency range 80MHz-1GHz and 1meter for frequency range 1.4GHz-2.7GHz away from the transmitting antenna. Through the signal generator, power amplifier and transmitting antenna to produce a uniformity field strength (3V/m measured by field sensor) around the EUT table from frequency range 80MHz-1000MHz,1.4GHz-2.7GHz and records the signal generator's output level at the same time for whole measured frequency range. Then, put EUT and its simulators on the EUT turn table and keep them 3 meters away from the transmitting antenna which is mounted on an antenna tower and fixed at 1 meter height above the ground. Using the recorded signal generator's output level to measure the EUT from frequency range 80MHz-1000MHz, 1.4GHz-2.7GHz and both horizontal & vertical polarization of antenna must be set and measured. Each of the four sides of EUT must be faced this transmitting antenna and measures individually.

In this report, chose the most sensible side to measure that is right side to face transmitting antenna.

All the scanning conditions are as follows :

Condition of Test	Remarks
Test Fielded Strength	3 V/m
Amplitude Modulated	1 kHz, 80%AM
Scanning Frequency	80 - 1000 MHz, 1.4GHz-2.7GHz
Step Size	1% increments
The Rate of Sweep	0.0015 decade/s
Dwell Time	3 Sec.

#### 8.7 Test Results

**PASS.**

The EUT was tested and all the test results are listed in next page.

## RF Field Strength Immunity Test Results

<i>Applicant</i>	<i>ASUSTeK COMPUTER INC.</i>		<i>Date of Test</i>	<i>2015.08.21</i>		
<i>EUT</i>	<i>Motherboard</i>		<i>Power rating</i>	<i>AC: 230 V ; 50Hz</i>		
<i>Model No.</i>	<i>H170I-PLUS D3</i>		<i>Temp.</i>	<i>23.8</i>	<i>Humidity</i>	<i>62 %</i>
<i>Test Mode</i>	<i>WLAN+BT Operating</i>					
<i>Working Condition</i>	<i>Operating</i>				<i>Results</i>	<i>PASS</i>
<i>Frequency Range (MHz)</i>	<i>E.U.T. Position ( Angle )</i>	<i>Ant. Polarity (Hor. or Ver.)</i>	<i>Field Strength (V/m)</i>	<i>Performance Criterion</i>		<i>Remark</i>
<i>80~1000</i>	<i>0</i>	<i>H</i>	<i>3</i>	<i>A</i>		
<i>80~1000</i>	<i>90</i>	<i>H</i>	<i>3</i>	<i>A</i>		
<i>80~1000</i>	<i>180</i>	<i>H</i>	<i>3</i>	<i>A</i>		
<i>80~1000</i>	<i>270</i>	<i>H</i>	<i>3</i>	<i>A</i>		
<i>80~1000</i>	<i>0</i>	<i>V</i>	<i>3</i>	<i>A</i>		
<i>80~1000</i>	<i>90</i>	<i>V</i>	<i>3</i>	<i>A</i>		
<i>80~1000</i>	<i>180</i>	<i>V</i>	<i>3</i>	<i>A</i>		
<i>80~1000</i>	<i>270</i>	<i>V</i>	<i>3</i>	<i>A</i>		
Note: I/O: RJ-45 port						
			<i>Engineer : Puck</i>			

## RF Field Strength Immunity Test Results

<i>Applicant</i>	<i>ASUSTeK COMPUTER INC.</i>		<i>Date of Test</i>	<i>2015.08.21</i>		
<i>EUT</i>	<i>Motherboard</i>		<i>Power rating</i>	<i>AC: 230 V ; 50Hz</i>		
<i>Model No.</i>	<i>H170I-PLUS D3</i>		<i>Temp.</i>	<i>23.8</i>	<i>Humidity</i>	<i>62 %</i>
<i>Test Mode</i>	<i>WLAN+BT Operating</i>					
<i>Working Condition</i>	<i>Operating</i>				<i>Results</i>	<i>PASS</i>
<i>Frequency Range (MHz)</i>	<i>E.U.T. Position ( Angle )</i>	<i>Ant. Polarity (Hor. or Ver.)</i>	<i>Field Strength (V/m)</i>	<i>Performance Criterion</i>		<i>Remark</i>
<i>1400~2700</i>	<i>0</i>	<i>H</i>	<i>3</i>	<i>A</i>		
<i>1400~2700</i>	<i>90</i>	<i>H</i>	<i>3</i>	<i>A</i>		
<i>1400~2700</i>	<i>180</i>	<i>H</i>	<i>3</i>	<i>A</i>		
<i>1400~2700</i>	<i>270</i>	<i>H</i>	<i>3</i>	<i>A</i>		
<i>1400~2700</i>	<i>0</i>	<i>V</i>	<i>3</i>	<i>A</i>		
<i>1400~2700</i>	<i>90</i>	<i>V</i>	<i>3</i>	<i>A</i>		
<i>1400~2700</i>	<i>180</i>	<i>V</i>	<i>3</i>	<i>A</i>		
<i>1400~2700</i>	<i>270</i>	<i>V</i>	<i>3</i>	<i>A</i>		
<i>Note :</i>						
			<i>Engineer : Puck</i>			



## 9 ELECTRICAL FAST TRANSIENT/BURST IMMUNITY TEST

### 9.1 Test Equipment

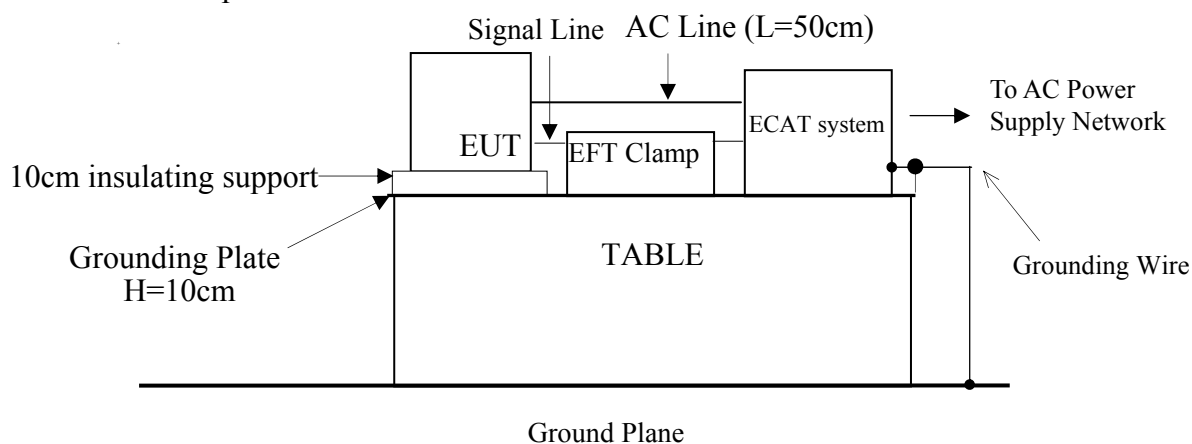
Item	Type	Manufacturer	Model No.	Serial No.	Last Cal.	Next Cal.
1.	EFT	3C TEST	EFT-4003G	EC0471226	2015-07-03	2016-07-03

### 9.2 Block Diagram of Test Setup

#### 9.2.1 Block Diagram of connection between EUT and simulators.

Same as section 8.2.1

#### 9.2.2 EFT Test Setup



Remark: Combination wave generator and decoupling networks are included.

### 9.3 Test Standard

ETSI EN 301 489-1V1.9.2:2011-09, clause 9.4 (EN61000-4-4:2012) & ETSI EN 301 489-17 V2.2.1:2012-09:2009

Severity Level 2 for L and N and L to N at 1kV

### 9.4 Severity Levels and Performance Criterion

#### 9.4.1 Severity level

Open Circuit Output Test Voltage $\pm 10\%$		
Level	On Power Supply Lines	On I/O (Input/Output) Signal data and control lines
1.	0.5 kV	0.25 kV
2.	1 kV	0.5 kV
3.	2 kV	1 kV
4.	4 kV	2 kV
X	Special	Special

#### 9.4.2 Performance criterion: **B**

## 9.5 Test Procedure

The EUT and its simulators were placed on the ground reference plane and were insulated from it by a wood support  $0.1\text{m} \pm 0.01\text{m}$  thick. The ground reference plane was  $1\text{m} \times 1\text{m}$  metallic sheet with 0.65mm minimum thickness. This reference ground plane was project beyond the EUT by at least 0.1m on all sides and the minimum distance between EUT and all other conductive structure, except the ground plane was more than 0.5m. All cables to the EUT was placed on the wood support, cables not subject to EFT/B was routed as far as possible from the cable under test to minimize the coupling between the cables.

### 9.5.1 For input and AC power ports:

The EUT was connected to the power mains by using a coupling device that couples the EFT interference signal to AC power lines. Both positive transients and negative transients of test voltage were applied during compliance test and the duration of the test can't less than 1min.

### 9.5.2 For signal lines and control lines ports:

Ports which are intended to be connected to telecommunication networks (e.g. public switched telecommunication networks, integrated services digital networks, local area networks and similar networks.)

### 9.5.3 For DC input and DC output power ports:

It's unnecessary to test.

## 9.6 Test Results

**PASS.**

The EUT was tested and all the test results are listed in next page.

## Electrical Fast Transient / Burst Immunity Test Results

Applicant	ASUSTeK COMPUTER INC.				Date of Test	2015.08.21				
EUT	Motherboard				Power rating	AC: 230 V ; 50 Hz				
Model No.	H170I-PLUS D3				Temp.	22.6		Humidity	48 %	
Test Mode	WLAN+BT Operating									
Working Condition	Operating				Results	PASS				
Inject Place: Power Supply Line					Inject Place: I/O Cable					
Inject Line	Voltage (kV)	Inject Time(s)	Inject Method	Performance Criterion	Inject Line	Voltage (kV)	Inject Time(s)	Inject Method	Performance Criterion	
L1	+0.5, +1.0	60	Direct	A	I/O	+0.25, +0.5	60	Clamp	A	
L1	-0.5, -1.0	60	Direct	A	I/O	-0.25, -0.5	60	Clamp	A	
L2	+0.5, +1.0	60	Direct	A						
L2	-0.5, -1.0	60	Direct	A						
PE	+0.5, +1.0	60	Direct	A						
PE	-0.5, -1.0	60	Direct	A						
L1,L2	+0.5, +1.0	60	Direct	A						
L1,L2	-0.5, -1.0	60	Direct	A						
L1,PE	+0.5, +1.0	60	Direct	A						
L1,PE	-0.5, -1.0	60	Direct	A						
L2,PE	+0.5, +1.0	60	Direct	A						
L2,PE	-0.5, -1.0	60	Direct	A						
L1,L2,PE	+0.5, +1.0	60	Direct	A						
L1,L2,PE	-0.5, -1.0	60	Direct	A						
Note: I/O: RJ-45 port					Engineer: Puck					

## 10 SURGE TEST

### 10.1 Test Equipment

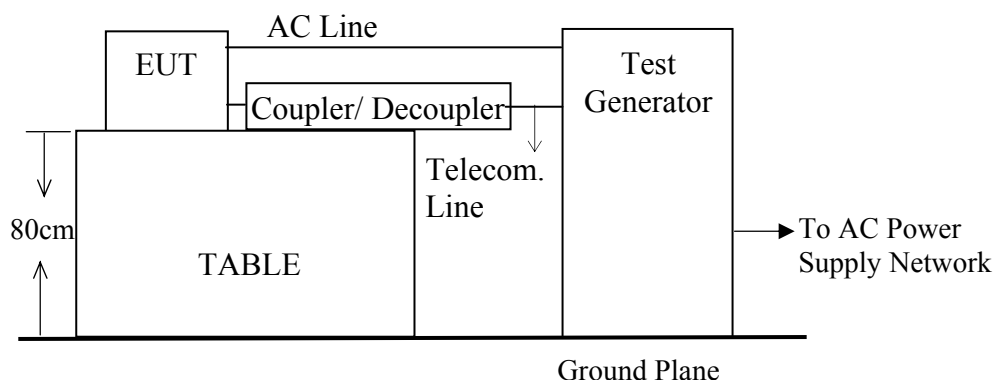
Item	Type	Manufacturer	Model No.	Serial No.	Last Cal.	Next Cal.
1.	Surge Generator	3C TEST	SG-5010G	EC5531208	2015-07-03	2016-07-03

### 10.2 Block Diagram of Test Setup

#### 10.2.1 Block Diagram of the EUT

Same as section 8.2.1

#### 10.2.2 Surge Test Setup



Remark: Test generator includes control center, surge combination and coupler.

### 10.3 Test Standard

ETSI EN 301 489-1 V1.9.2:2011-09, clause 9.8 (EN 61000-4-5:2006) &

ETSI EN 301 489-17 V2.2.1:2012-09

Severity Level: Line to Line: Level 2 at 1kV

Line to Ground: Level 3 at 2kV)

### 10.4 Severity Levels and Performance Criterion

#### 10.4.1 Severity level

Severity Level	Open-Circuit Test Voltage kV
1	0.5
2	1.0
3	2.0
4	4.0
*	Special

#### 10.4.2 Performance criterion: **B**

#### 10.5 Test Procedure

- (1) Set up the EUT and test generator as shown on Section 10.2.2.
- (2) For line-to-line coupling mode, provide a 1kV 1.2/50us voltage surge (at open-circuit condition) and 8/20us current surge to EUT selected points, and for active line / neutral lines to ground are same except test level is 2kV.
- (3) At least 5 positive and 5 negative (polarity) tests with a maximum 1/min repetition rate are applied during test.
- (4) Different phase angles are done individually.
- (5) Record the EUT operating situation during compliance test and decide the EUT immunity criterion for above each test.

#### 10.6 Test Results

**PASS.**

The EUT was tested and all the test results are listed in next page.

## Surge Immunity Test Results

Applicant	ASUSTeK COMPUTER INC.			Date of Test	2015.08.21	
EUT	Motherboard			Power rating	AC: 230 V ; 50Hz	
Model No.	H170I-PLUS D3			Temp.	22.6	Humidity 48 %
Test Mode	WLAN+BT Operating					
Working Condition	Operating			Results	PASS	
<i>Input and Output AC Power Port</i>						
Location	Polarity	Phase Angle	No of Pulse	Pulse Voltage		Performance Criterion
L-N	+	0	5	0.5kV, 1.0kV		A
	+	90	5	0.5kV, 1.0kV		A
	+	180	5	0.5kV, 1.0kV		A
	+	270	5	0.5kV, 1.0kV		A
		0	5	0.5kV, 1.0kV		A
		90	5	0.5kV, 1.0kV		A
		180	5	0.5kV, 1.0kV		A
		270	5	0.5kV, 1.0kV		A
L-PE	+	0	5	0.5kV, 1.0kV, 2.0kV		A
	+	90	5	0.5kV, 1.0kV, 2.0kV		A
	+	180	5	0.5kV, 1.0kV, 2.0kV		A
	+	270	5	0.5kV, 1.0kV, 2.0kV		A
		0	5	0.5kV, 1.0kV, 2.0kV		A
		90	5	0.5kV, 1.0kV, 2.0kV		A
		180	5	0.5kV, 1.0kV, 2.0kV		A
		270	5	0.5kV, 1.0kV, 2.0kV		A
N-PE	+	0	5	0.5kV, 1.0kV, 2.0kV		A
	+	90	5	0.5kV, 1.0kV, 2.0kV		A
	+	180	5	0.5kV, 1.0kV, 2.0kV		A
	+	270	5	0.5kV, 1.0kV, 2.0kV		A
		0	5	0.5kV, 1.0kV, 2.0kV		A
		90	5	0.5kV, 1.0kV, 2.0kV		A
		180	5	0.5kV, 1.0kV, 2.0kV		A
		270	5	0.5kV, 1.0kV, 2.0kV		A
L, N-PE	+	0	5	0.5kV, 1.0kV, 2.0kV		A
	+	90	5	0.5kV, 1.0kV, 2.0kV		A
	+	180	5	0.5kV, 1.0kV, 2.0kV		A
	+	270	5	0.5kV, 1.0kV, 2.0kV		A
		0	5	0.5kV, 1.0kV, 2.0kV		A
		90	5	0.5kV, 1.0kV, 2.0kV		A
		180	5	0.5kV, 1.0kV, 2.0kV		A
		270	5	0.5kV, 1.0kV, 2.0kV		A
				Engineer: Puck		

## Surge Immunity Test Results 2

<i>Applicant</i>	ASUSTeK COMPUTER INC.		<i>Date of Test</i>	2015.08.21	
<i>EUT</i>	Motherboard		<i>Power rating</i>	AC: 230 V ; 50Hz	
<i>Model No.</i>	H170I-PLUS D3		<i>Temp.</i>	22.6	<i>Humidity</i> 48 %
<i>Test Mode</i>	WLAN+BT Operating				
<i>Working Condition</i>	Operating		<i>Results</i>	PASS	
<i>Telecom Line Coupling</i>					
<i>Line</i>	<i>Polarity</i>	<i>No of Pulse</i>	<i>Pulse Voltage</i>		<i>Performance</i>
					<i>Criterion</i>
<i>T1</i>	+	5	0.5kV	1kV	N/A
	-	5	0.5kV	1kV	N/A
<i>R1</i>	+	5	0.5kV	1kV	N/A
	-	5	0.5kV	1kV	N/A
<i>T2</i>	+	5	0.5kV	1kV	N/A
	-	5	0.5kV	1kV	N/A
<i>R2</i>	+	5	0.5kV	1kV	N/A
	-	5	0.5kV	1kV	N/A
<i>T1, R1</i>	+	5	0.5kV	1kV	N/A
	-	5	0.5kV	1kV	N/A
<i>T2, R2</i>	+	5	0.5kV	1kV	N/A
	-	5	0.5kV	1kV	N/A
<i>T1, R1, T2, R2</i>	+	5	0.5kV	1kV	N/A
	-	5	0.5kV	1kV	N/A
<i>[ ]DC Input and Output Power Port   [ ]I/O Signal Cable</i>					
<i>Location</i>	<i>Polarity</i>	<i>No of</i>	<i>Pulse Voltage</i>		<i>Performance</i>
		<i>Pulse</i>			<i>Criterion</i>
<i>Differential</i>	+	5	0.5kV	1kV	N/A
<i>Mode</i>	-	5	0.5kV	1kV	N/A
<i>Common</i>	+	5	0.5kV	1kV	A
<i>Mode</i>	-	5	0.5kV	1kV	A
<i>Note :</i>					
1. N/A means not applicable.					
2. I/O:RJ-45 port					
			<i>Engineer: Puck</i>		

# 11 INJECTED CURRENTS SUSCEPTIBILITY TEST

## 11.1 Test Equipment

Item	Type	Manufacturer	Model No.	Serial No.	Last Cal.	Next Cal.
1.	Signal Generator	Agilent	8648C	3847M01438	2015-01-05	2016-01-04
2.	Power Amplifier	AR	KAW 2180	10088-2	NCR	NCR
3.	Attenuator	ShanghaiHua xiang	DTS150	6092701	2015-01-05	2016-01-04
4.	CDN-M2	FCC	FCC-801-M3-25A	06041	2015-01-05	2016-01-04
5.	CDN-M3	FCC	FCC-801-M3-25A	06042	2015-01-05	2016-01-04
6.	Decoupling Network	FCC	F-203I-23MM-DC N	196	2015-01-05	2016-01-04
7.	EM Injection Clamp	FCC	F-203I-03MM	503	2015-01-05	2016-01-04
8.	Software	i2(4.110314)				

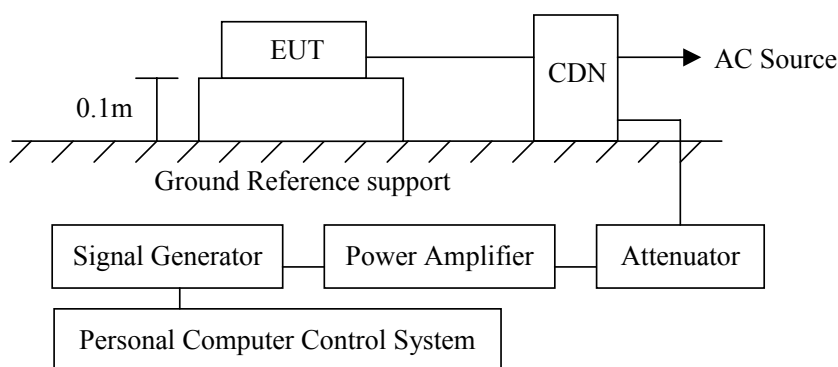
NCR: Non-Calibration Requirement.

## 11.2 Block Diagram of Test Setup

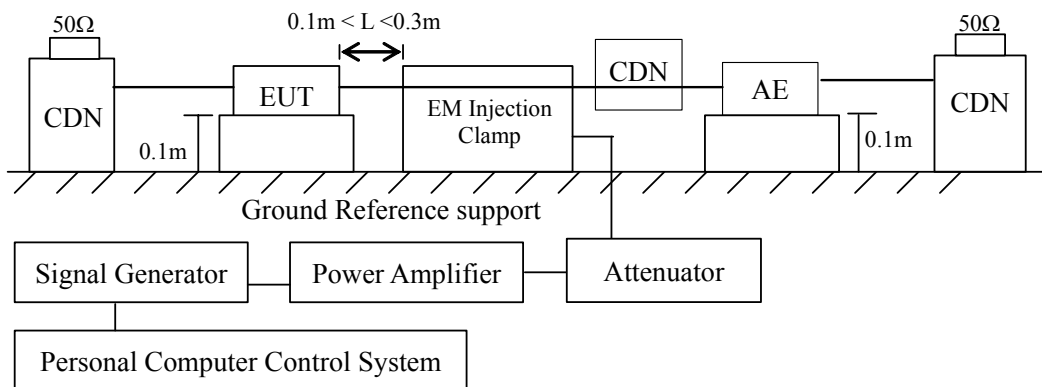
### 11.2.1 Block Diagram of connection between EUT and simulators.

Same as Section 8.2.1

### 11.2.2 Common Mode Test Setup



### 11.2.3 EM Clamp Mode Test Setup





### 11.3 Test Standard

ETSI EN 301 489-1 V1.9.2:2011-09, clause 9.5 (EN 61000-4-6:2014) &  
ETSI EN 301 489-17 V2.2.1:2012-09  
Severity Level 2 at 3 V (rms) and frequency is from 0.15MHz to 80MHz)

### 11.4 Severity Levels and Performance Criterion

#### 11.4.1 Severity level

Level	Voltage Level (e.m.f.) V
1.	1
2.	3
3.	10
X	Special

#### 11.4.2 Performance criterion: A

### 11.5 Test Procedure

- 1) Setup the EUT, CDN and test generators as shown on Section 11.2.2.
- 2) Let the EUT work in test mode and test it.
- 3) The EUT are placed on an insulating support 0.1m high above a ground reference plane. CDN (coupling and decoupling device) is placed on the ground plane about 0.3m from EUT. Cables between CDN and EUT are as short as possible, and their height above the ground reference plane shall be between 30 and 50 mm (where possible).
- 4) The disturbance signal described below is injected to EUT through CDN.
- 5) The EUT operates within its operational mode(s) under intended climatic conditions after power on.
- 6) The frequency range is swept from 0.150MHz to 80MHz using 3V signal level, and with the disturbance signal 80% amplitude modulated with a 1 kHz sine wave.
- 7) The rate of sweep shall not exceed  $1.5 \times 10^{-3}$  decades/s. Where the frequency is swept incrementally; the step size shall not exceed 1% of the start and thereafter 1% of the preceding frequency value.
- 8) Recording the EUT operating situation during compliance testing and decide the EUT immunity criterion.

### 11.6 Test Results

**PASS.**

The EUT was tested and all the test results are listed in next page.

## Inject Currents Immunity Test Results

<i>Applicant</i>	ASUSTeK COMPUTER INC.		<i>Date of Test</i>	2015.08.21	
<i>EUT</i>	Motherboard		<i>Power rating</i>	AC: 230V ; 50Hz	
<i>Model No.</i>	H170I-PLUS D3	<i>Temp.</i>	23.8	<i>Humidity</i>	62 %
<i>Test Mode</i>	WLAN+BT Operating				
<i>Working Condition</i>	Operating		<i>Results</i>	PASS	
<i>Frequency Range (MHz)</i>	<i>Inject Position</i>	<i>Strength</i>	<i>Performance Criterion</i>	<i>Remark</i>	
0.15MHz~80MHz	Main	3V	A	Power	
0.15MHz~230MHz	Main	3V	N/A		
0.15MHz~80MHz	I/O	3V	A	RJ-45	
0.15MHz~230MHz	I/O	3V	N/A		
<i>Note:</i> I/O: RJ-45 port					
		<i>Engineer : Puck</i>			

## 12 VOLTAGE DIPS AND INTERRUPTIONS TEST

### 12.1 Test Equipment

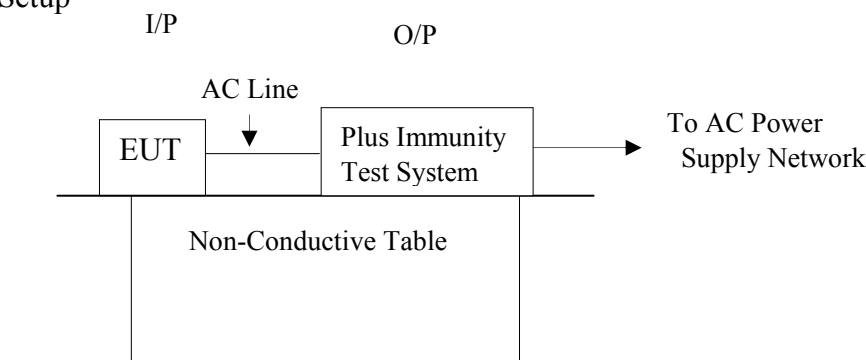
Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Next Cal.
1.	AC power source	TESEQ	NSG1007-45-3PI	1236A00705	2013-09-17	2015-09-17

### 12.2 Block Diagram of Test Setup

#### 12.2.1 Block Diagram of connection between EUT and simulators.

Same as section 8.2.1.

#### 12.2.2 Test Setup



### 12.3 Test Standard

ETSI EN 301 489-1 V1.9.2:2011-09, clause 9.7 (EN 61000-4-11:2004) & ETSI EN 301 489-17 V2.2.1:2012-09

### 12.4 Severity Levels and Performance Criterion

#### 12.4.1 Severity level

Test Level %U <sub>T</sub>	Voltage dip and short interruptions %U <sub>T</sub>	Performance Criterion	Duration (in period)
0	100	B	0.5
0	100	B	1
70	30	B	5
0	100	C	250

Performance criterion: **B & C**

### 12.5 Test Procedure

- 1) The EUT and test generator were setup as shown on Section 12.2.2.
- 2) The interruptions are introduced at selected phase angles with specified duration.
- 3) Record any degradation of performance.

### 12.6 Test Results

**PASS.**

The EUT was tested and all the test results are listed in next page.

## Voltage Dips and Interruptions Immunity Test Results

<i>Applicant</i>	ASUSTeK COMPUTER INC.		<i>Date of Test</i>	2015.08.21	
<i>EUT</i>	Motherboard		<i>Power rating</i>	AC: 230 V ; 50 Hz	
<i>Model No.</i>	H170I-PLUS D3		<i>Temp.</i>	22.6	<i>Humidity</i> 48 %
<i>Test Mode</i>	WLAN+BT Operating				
<i>Working Condition</i>	Operating		<i>Results</i>	PASS	
<i>Type of Test</i>	<i>Test Voltage</i>				<i>Performance Criterion</i>
		<i>Phase Angle</i>	<i>% Reduction</i>	<i>Period</i>	
<i>Voltage Interruption</i>	230	0	>95%	250	C
		45	>95%	250	C
		90	>95%	250	C
		135	>95%	250	C
		180	>95%	250	C
		225	>95%	250	C
		270	>95%	250	C
		315	>95%	250	C
<i>Voltage Dips</i>	230	0	30%	25	A
		45	30%	25	A
		90	30%	25	A
		135	30%	25	A
		180	30%	25	A
		225	30%	25	A
		270	30%	25	A
		315	30%	25	A
	230	0	>95%	0.5	A
		45	>95%	0.5	A
		90	>95%	0.5	A
		135	>95%	0.5	A
		180	>95%	0.5	A
		225	>95%	0.5	A
		270	>95%	0.5	A
		315	>95%	0.5	A
<i>Note:</i>					
The performance criterion "C" means the power of the EUT is turned off, and it cannot recover by itself during the test interval .					
			<i>Engineer Puck</i>		

## 13 PHOTOGRAPHS

### 13.1 Photos of Conducted Disturbance Measurement



Front View of Conducted Measurement (AC Mains Port)



Side View of Conducted Measurement (AC Mains Port)



Front View of Conducted Emission Measurement (Telecommunication port)



Side View of Conducted Emission Measurement (Telecommunication port)

13.2 Photos of Radiated Disturbance Measurement  
For 30MHz ~1GHz

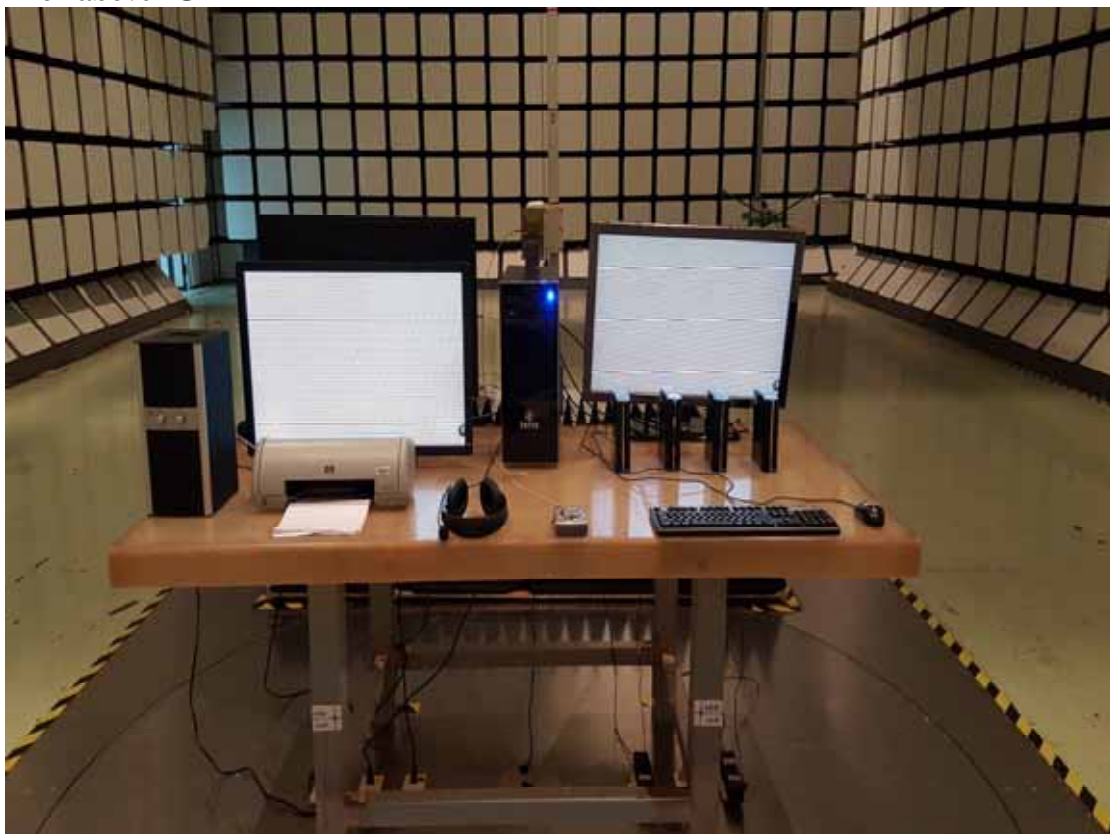


Front View of Radiated Disturbance Measurement



Back View of Radiated Disturbance Measurement

For above 1GHz



Front View of Radiated Disturbance Measurement



Back View of Radiated Disturbance Measurement



### 13.3 Photos of Harmonic & Flicker Measurement



### 13.4 Photos of Electrostatic Discharge Immunity Test

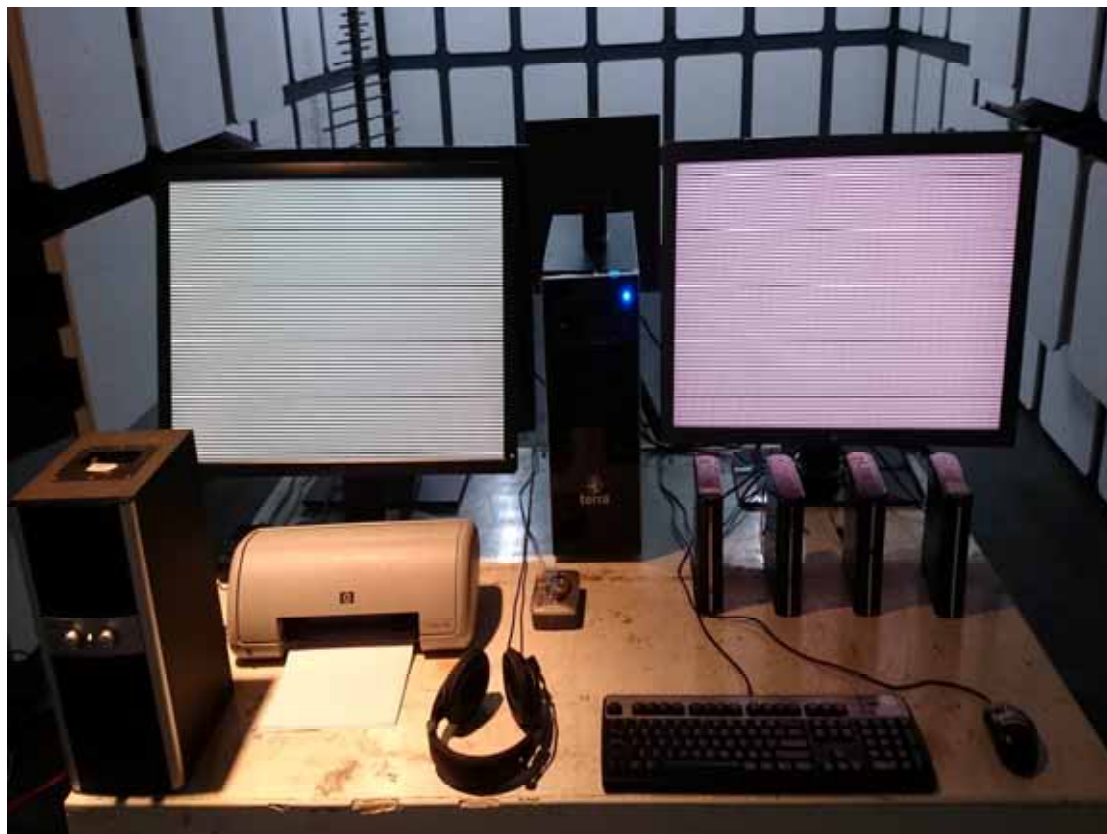


Contact & Air Discharge



VCP & HCP

### 13.5 Photos of RF Field Strength Immunity Test



Front View of R/S Test

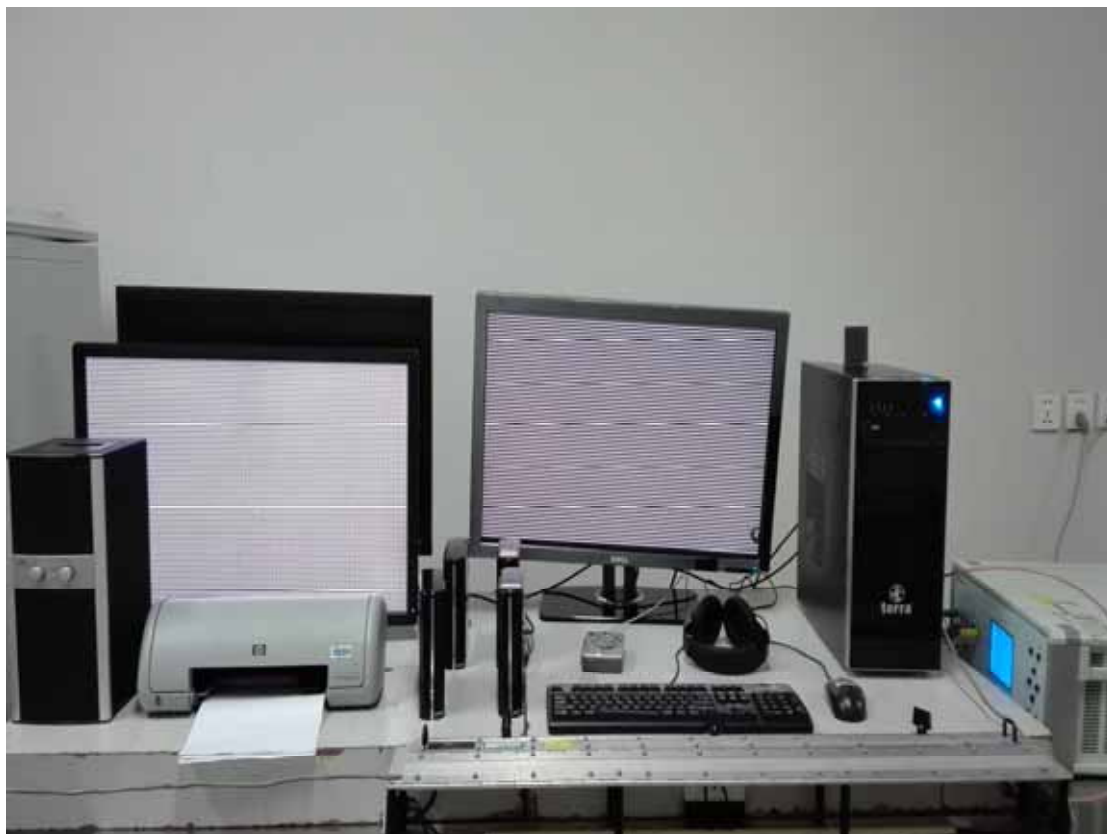


Back View of R/S Test

### 13.6 Photos of Electrical Fast Transient Immunity Test



For AC Mains port



For Telecommunication port

### 13.7 Photos of Surge Immunity Test



For AC Mains port



For Telecommunication port

### 13.8 Photos of Conducted Disturbance Immunity Test



For AC Mains port



For Telecommunication port

### 13.9 Photos of Power Frequency Magnetic Field Immunity Test



13.10 Photos of Voltage Dips and Interruptions Immunity Test



13.11 Photos of Host PC for RJ-45 Ping Test



# APPENDIX

## Photos of EUT



Figure 1  
General Appearance (Motherboard, Front View)



Figure 2  
General Appearance (Motherboard, Back View)



Figure 3  
General Appearance (Motherboard, Fan Set Removed)



Figure 4  
Fan Set(Front View)



Figure 5  
Fan Set(Back View)



Figure 6  
General Appearance (Motherboard, I/O Ports)



Figure 7  
CPU(Front View)



Figure 8  
CPU (Back View)

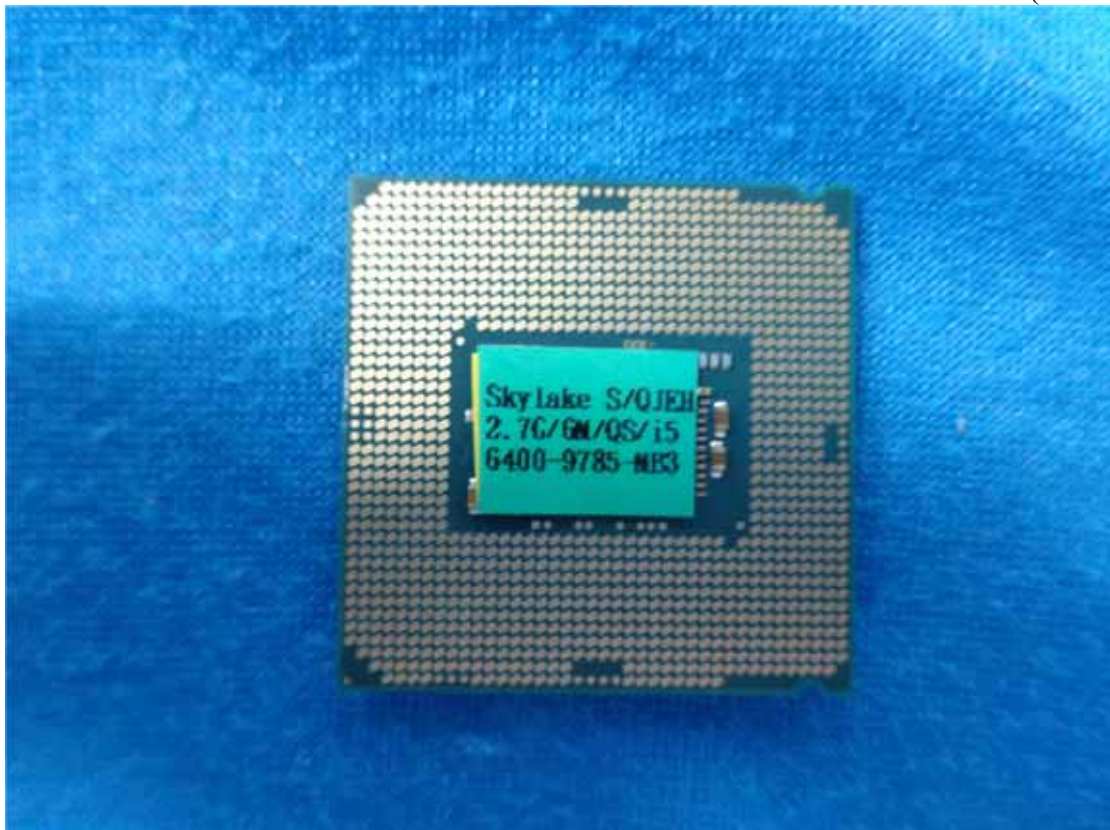


Figure 9  
Crystal Oscillator

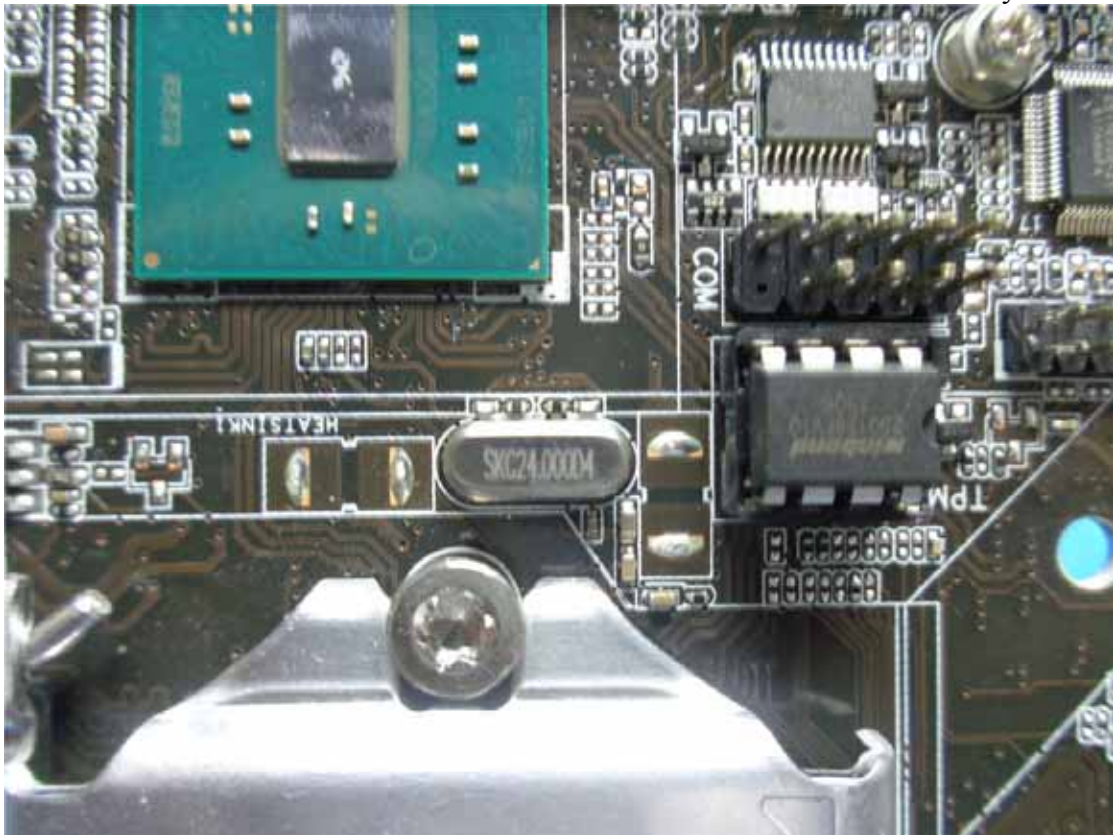


Figure 10  
Crystal Oscillator

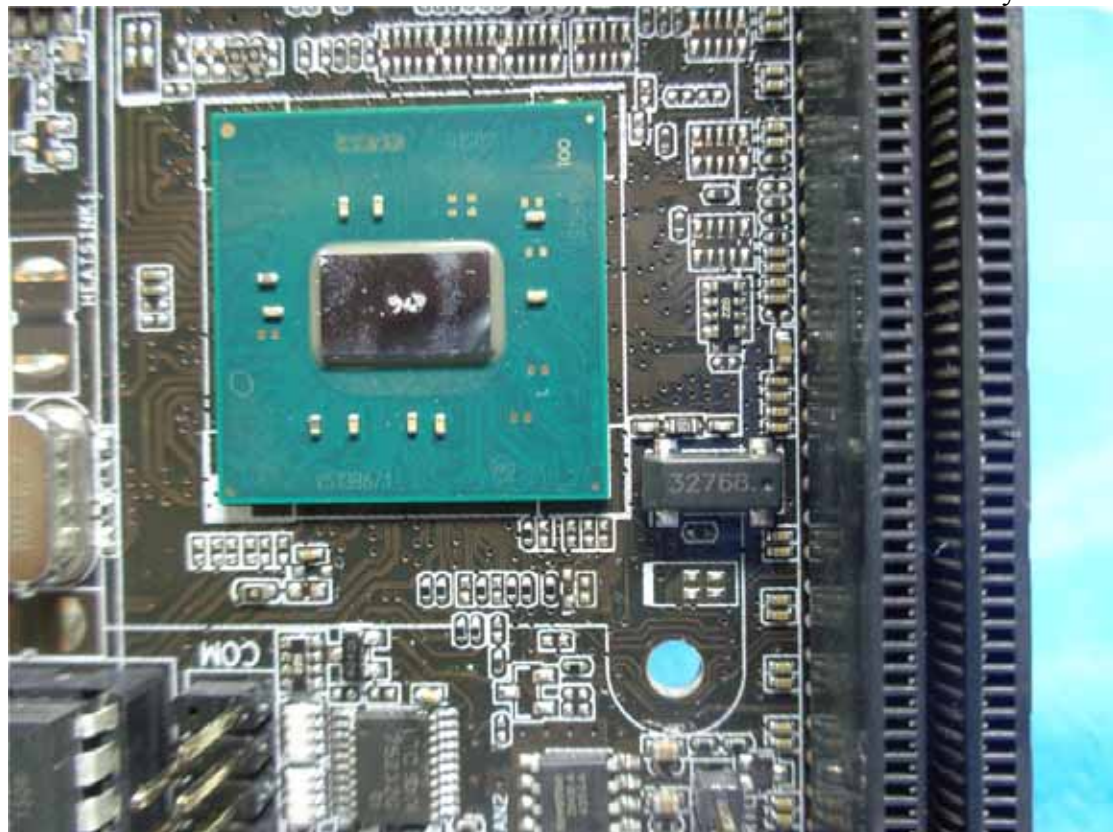


Figure 11  
Crystal Oscillator

